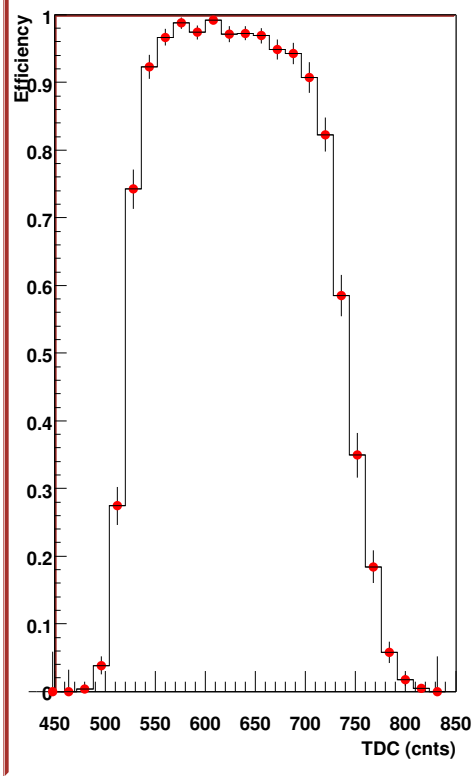
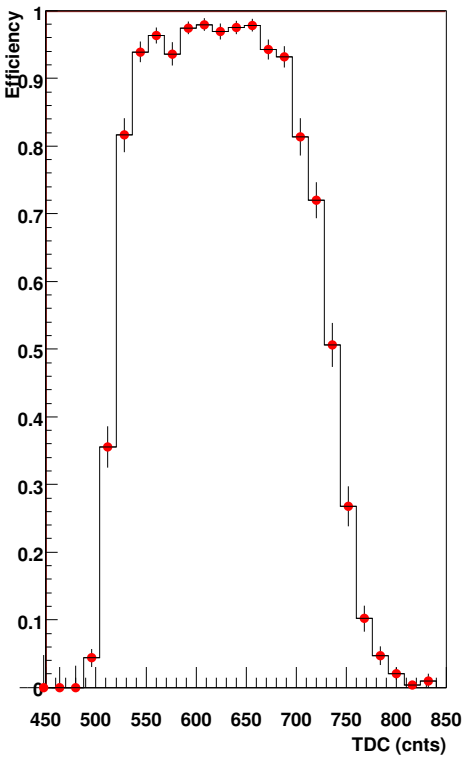
KEK3103-0 bias scan 1fC, max angle, no field

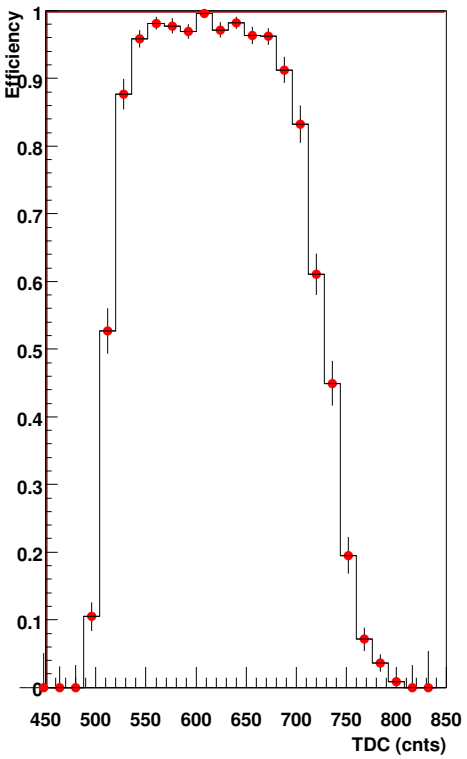
100 V (1778) : 44.7 ns



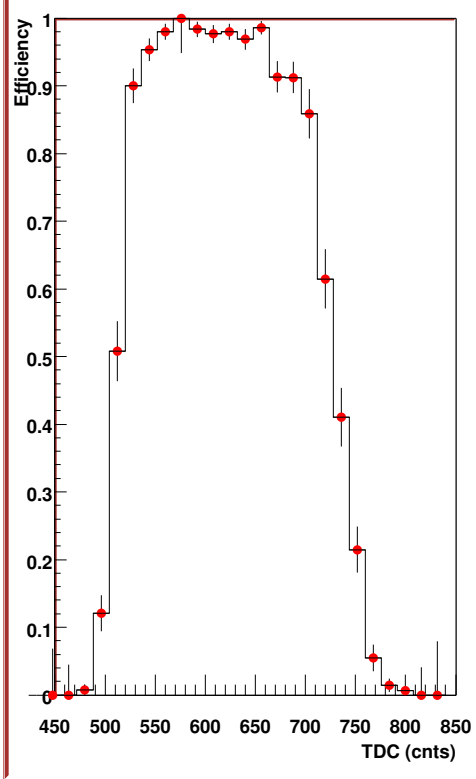
120 V (1796) : 43.9 ns



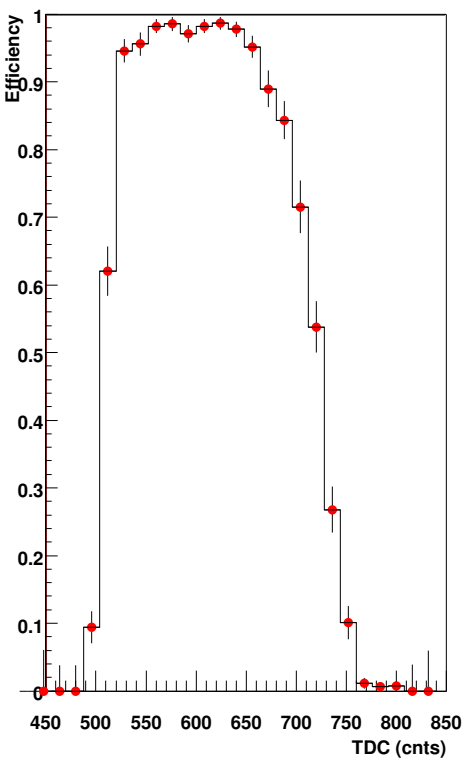
140 V (1814) : 43.6 ns



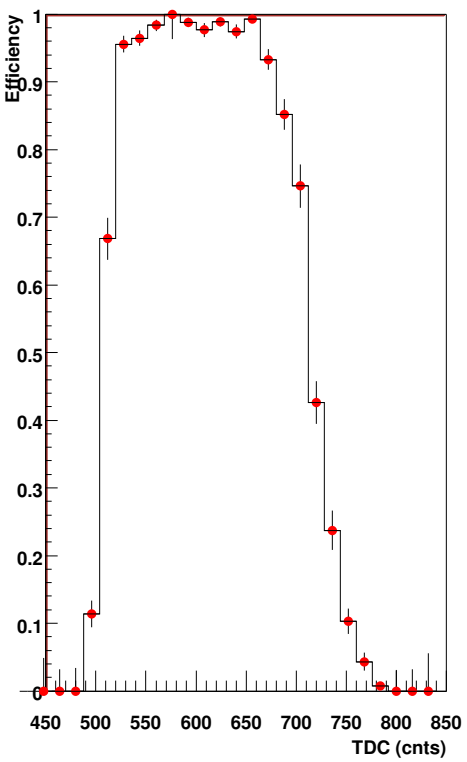
160 V (1833) : 43.8 ns



200 V (1919) : 42.0 ns

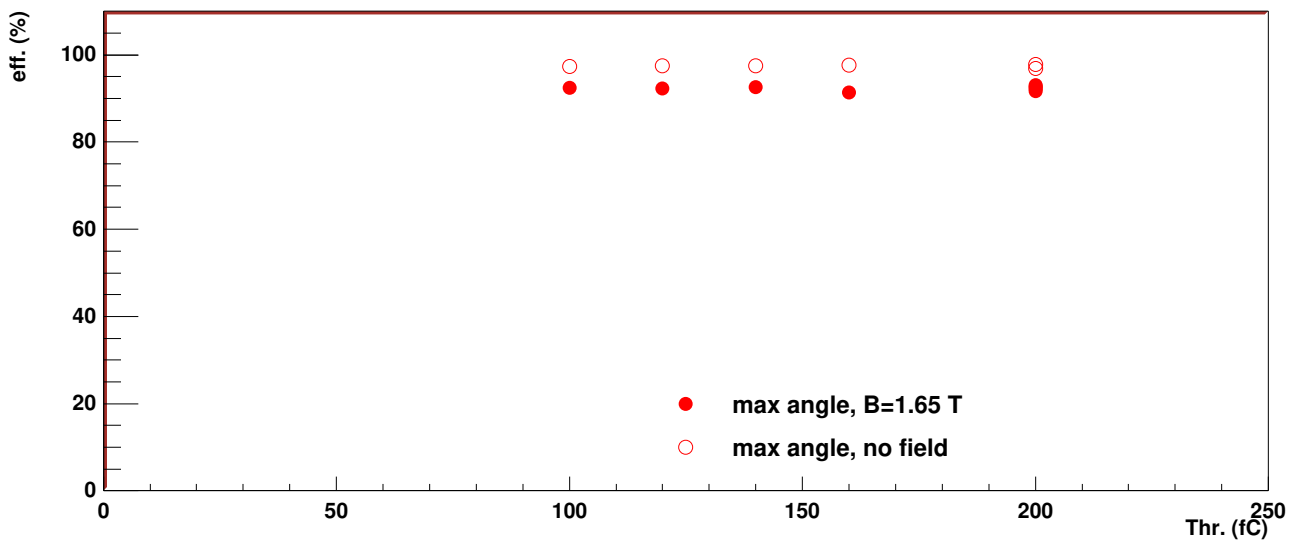


200 V (1913) : 42.1 ns

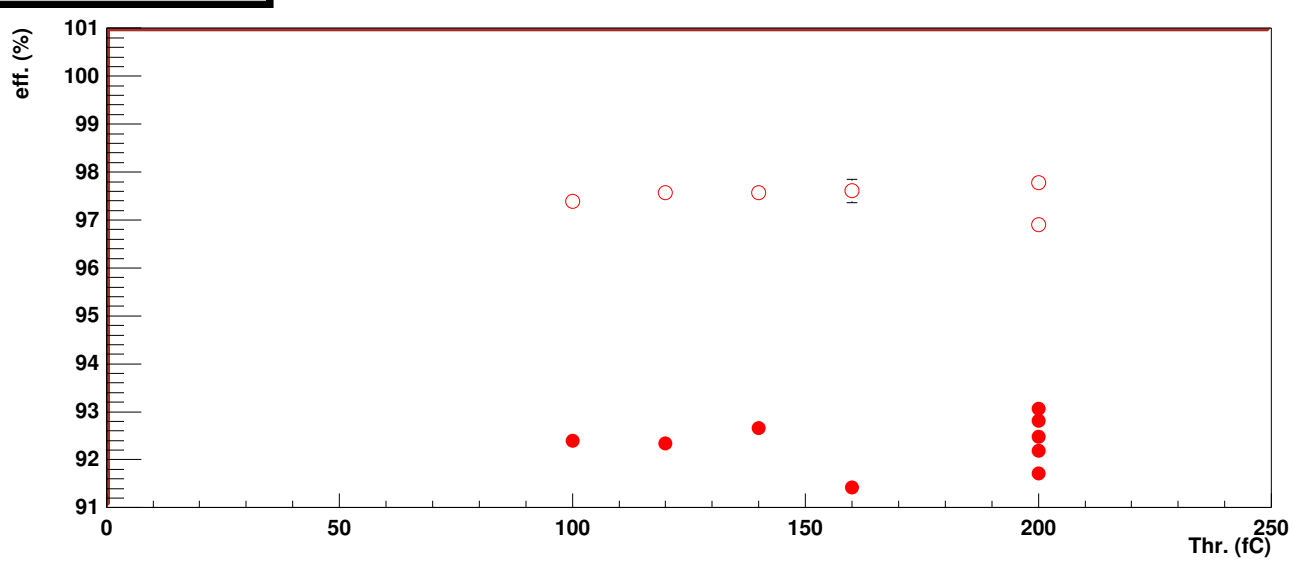


KEK3103: Bias scan 1 fC, max angle

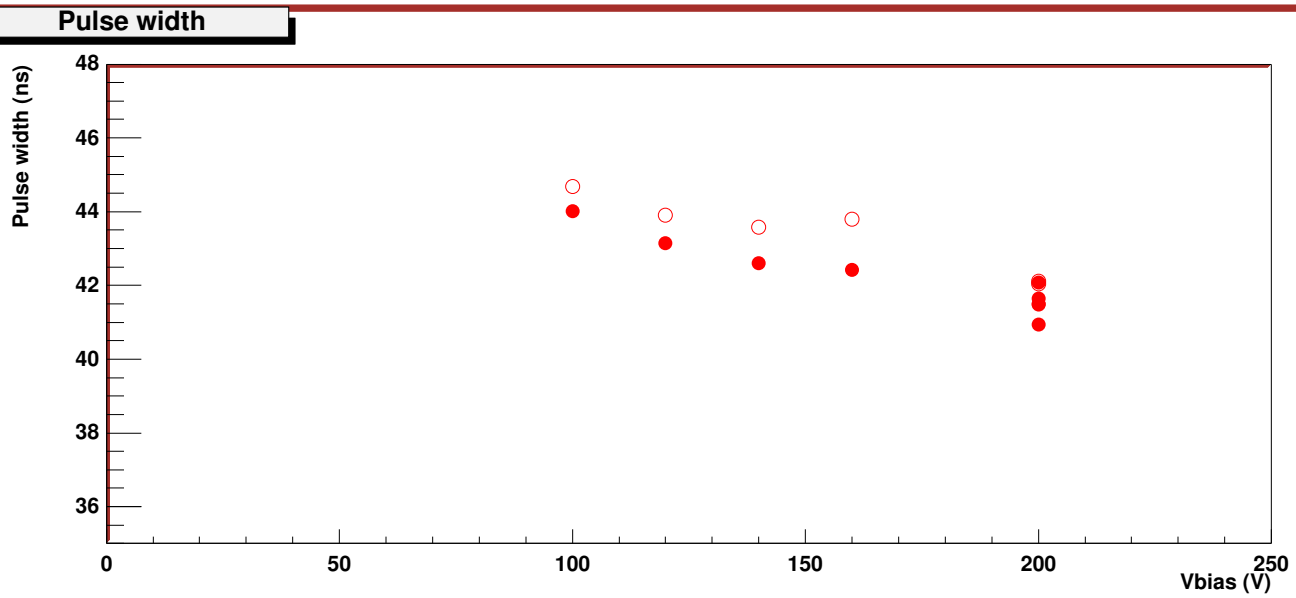
Efficiency



Efficiency

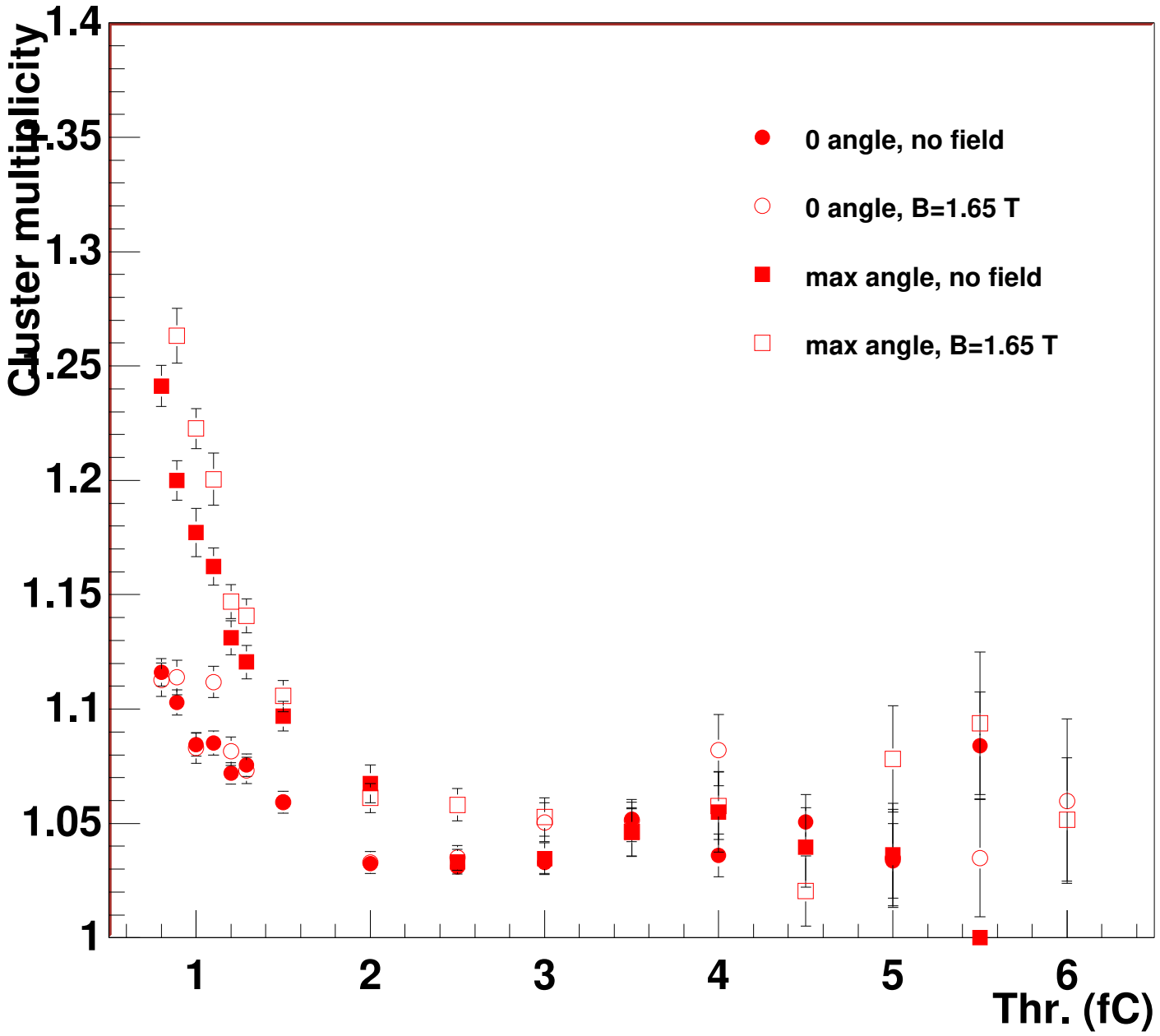


Pulse width

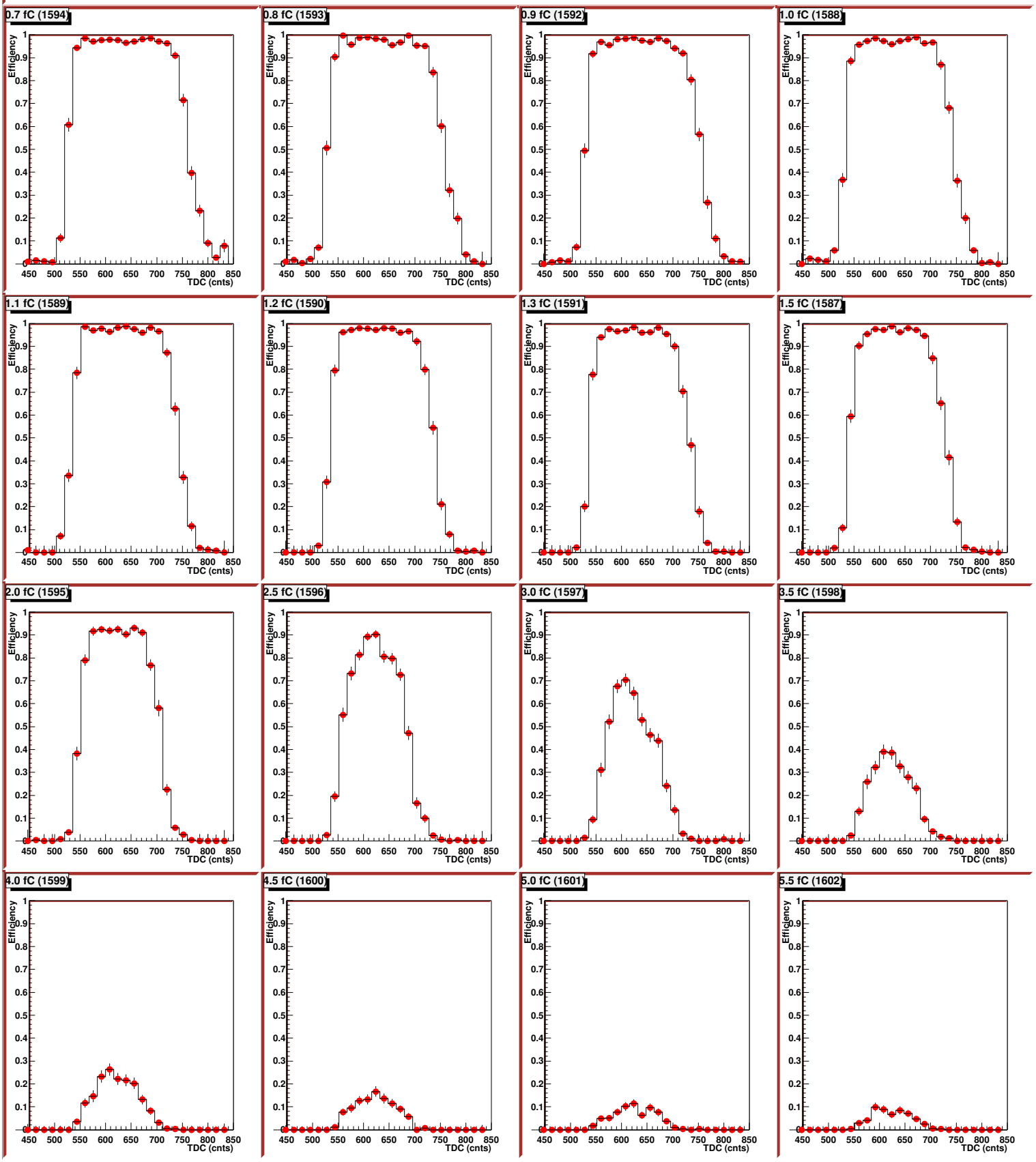


KEK3103: Av. cluster multiplicity 160 V

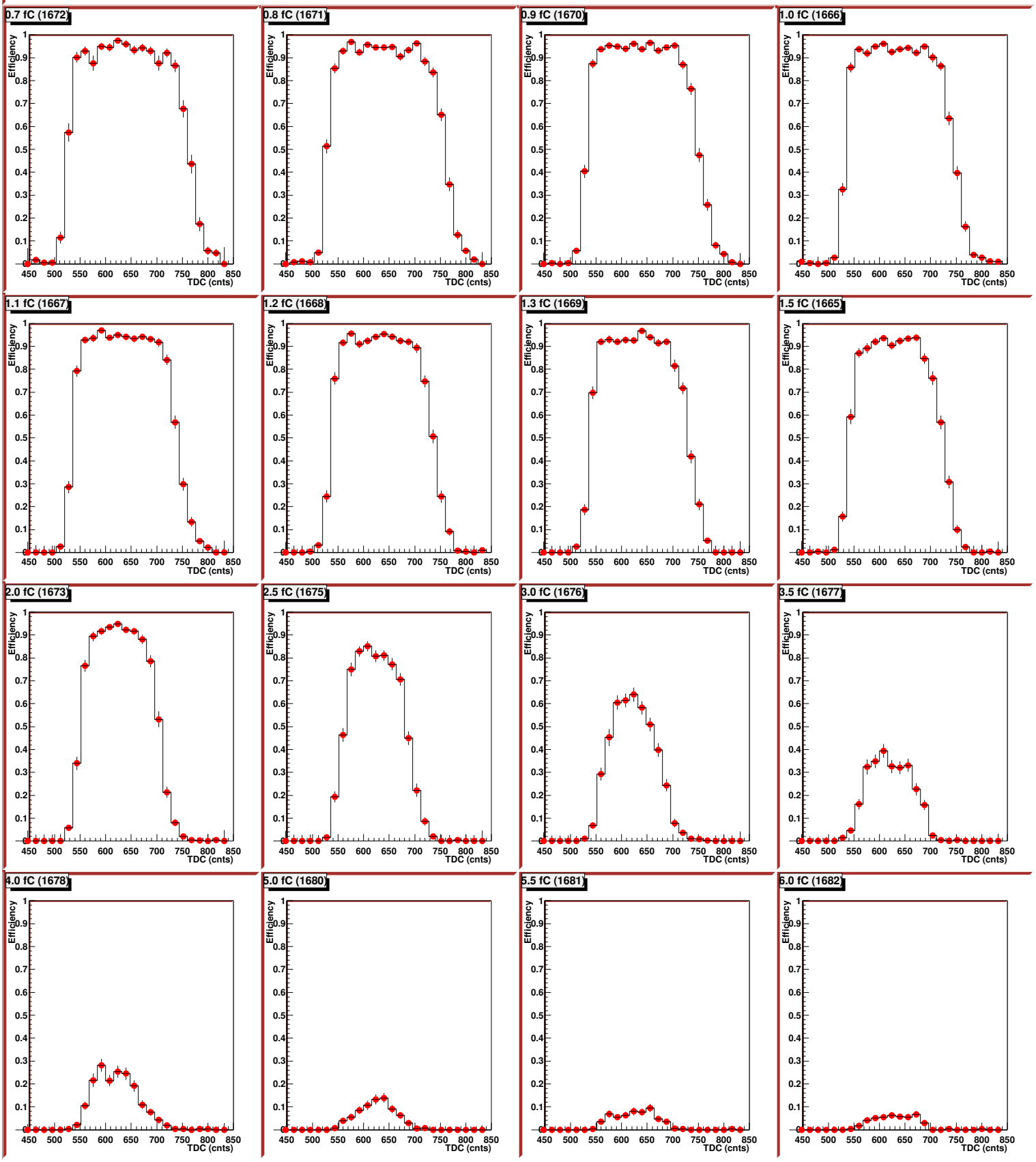
efficient clusters



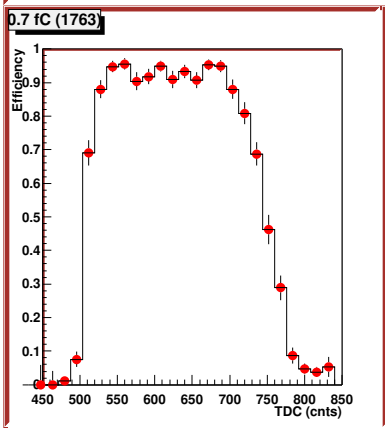
KEK3103-0 threshold scan 160 V, 0 angle, no field

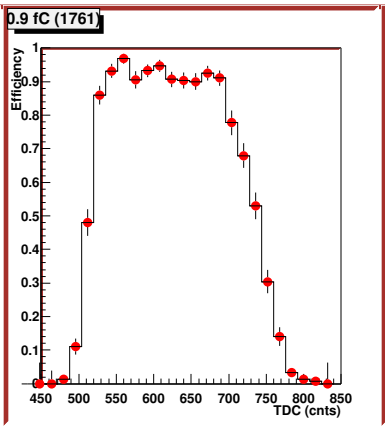


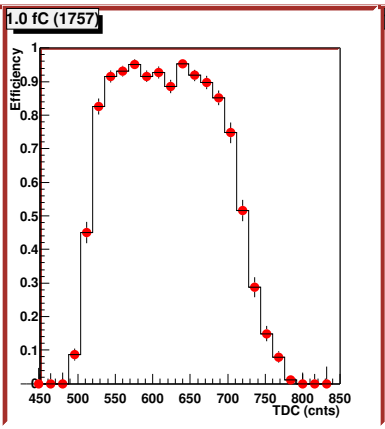
KEK3103-0 threshold scan 160 V, 0 angle, B=1.65 T

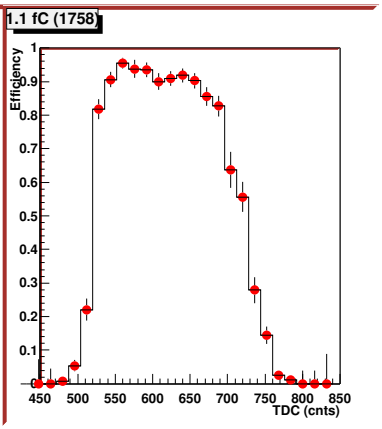


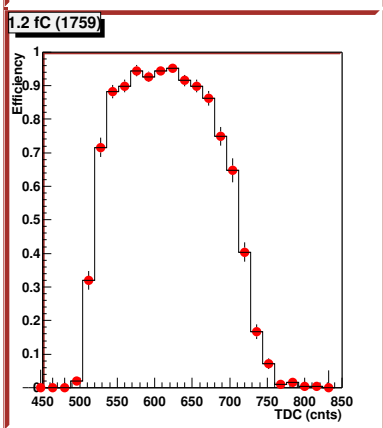
KEK3103-0 threshold scan 160 V, max angle, B=1.65 T

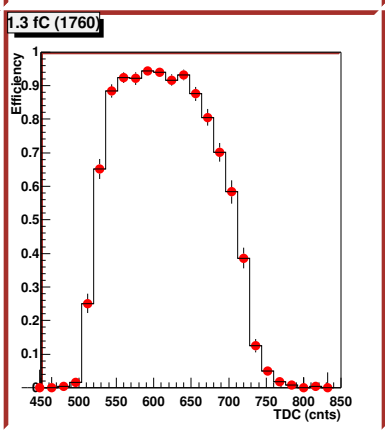


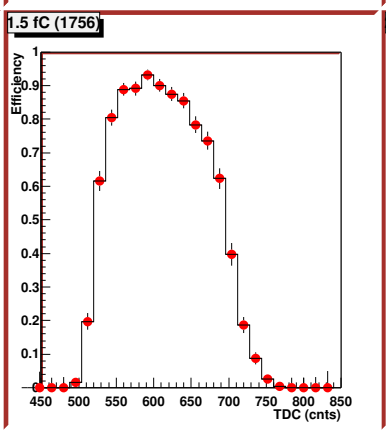


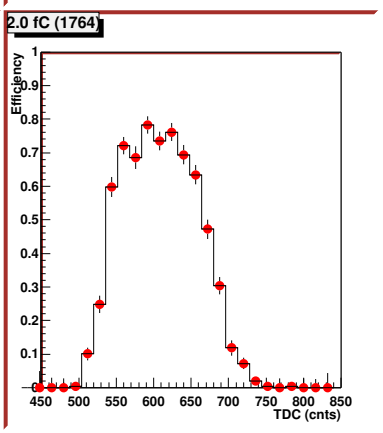


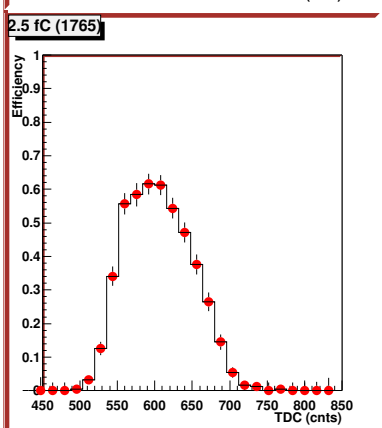


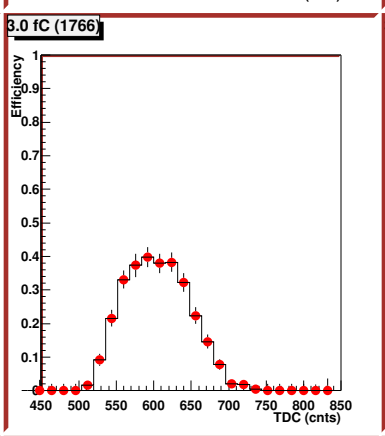


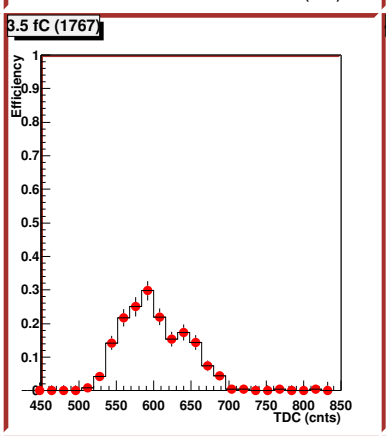


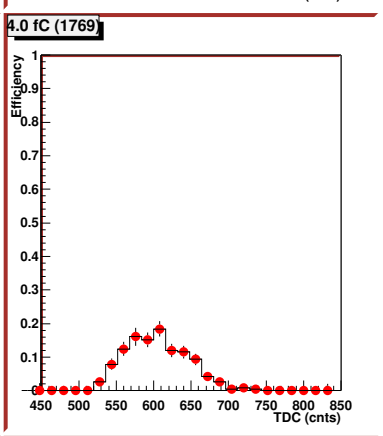


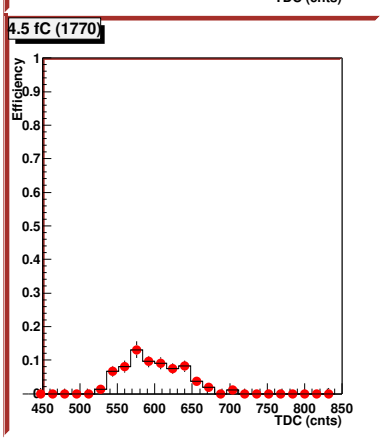


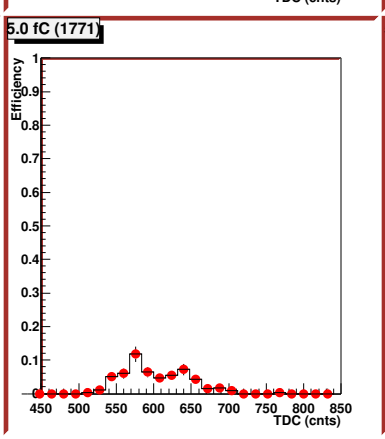


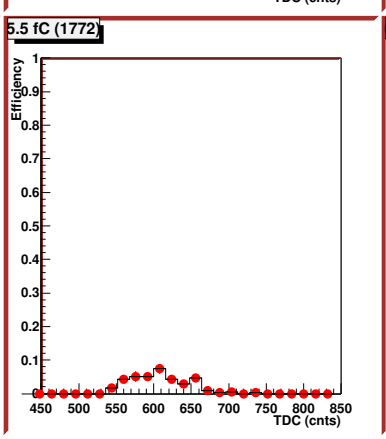


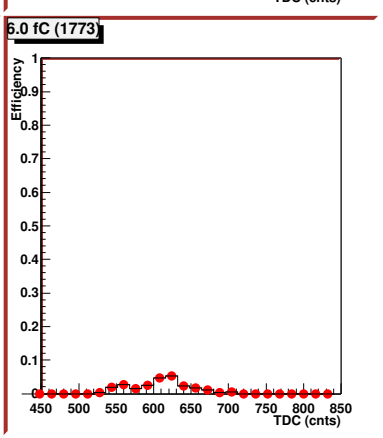




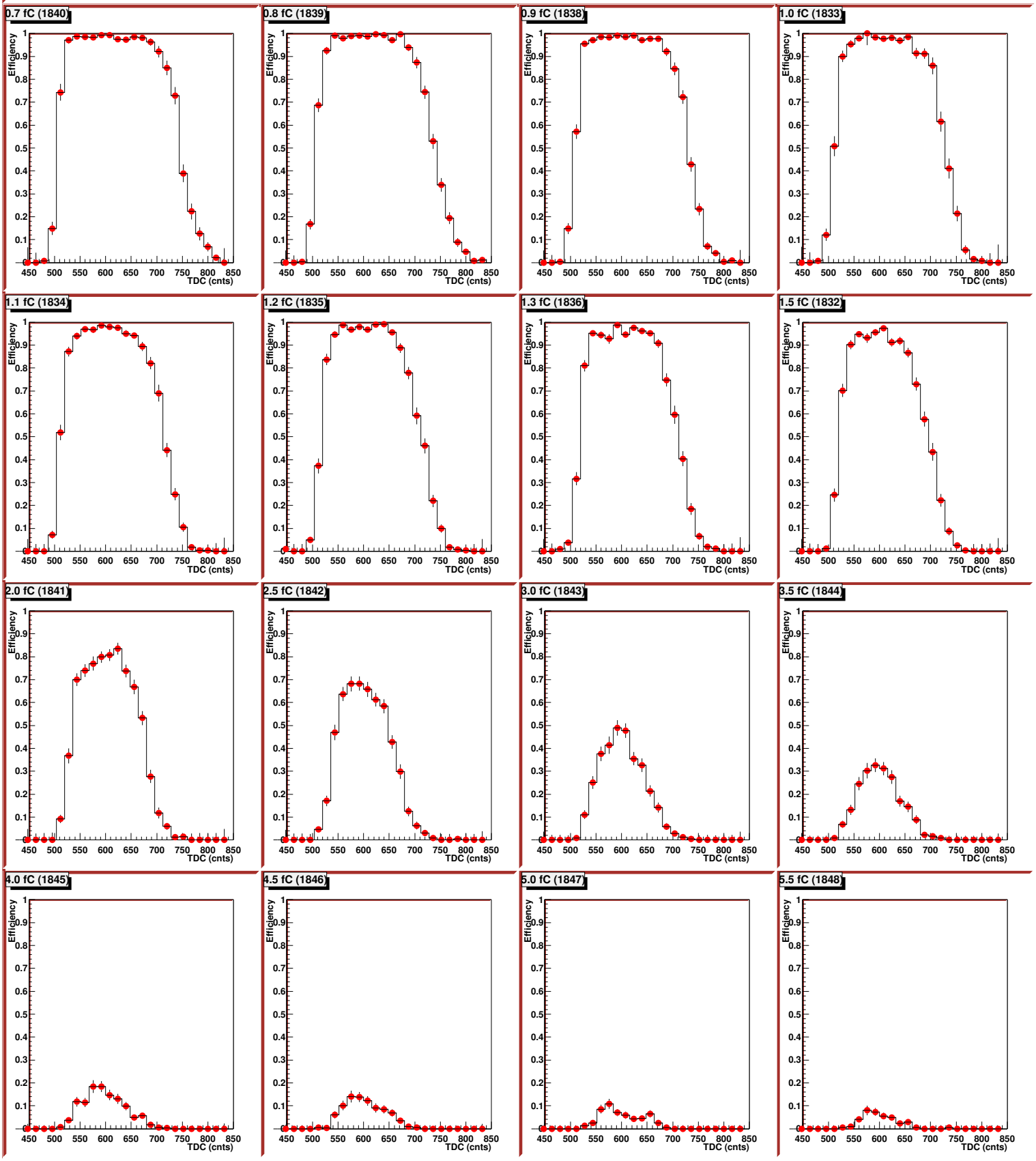






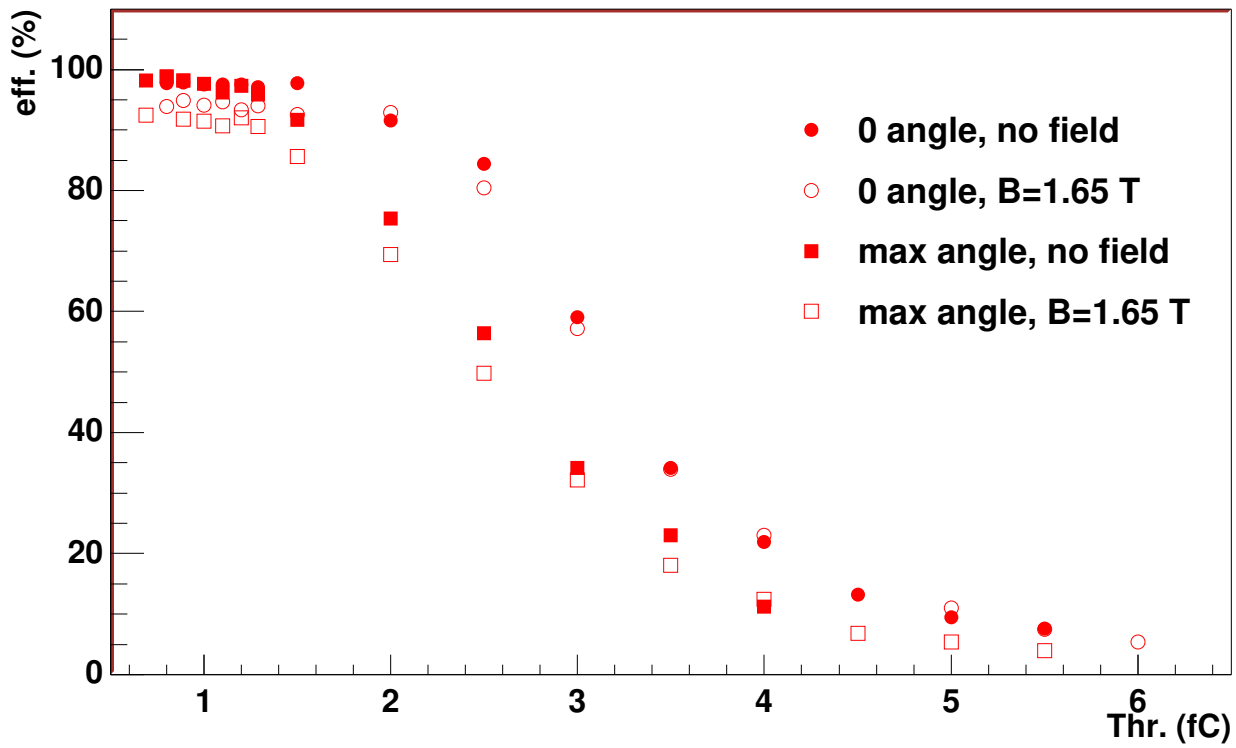


KEK3103-0 threshold scan 160 V, max angle, no field

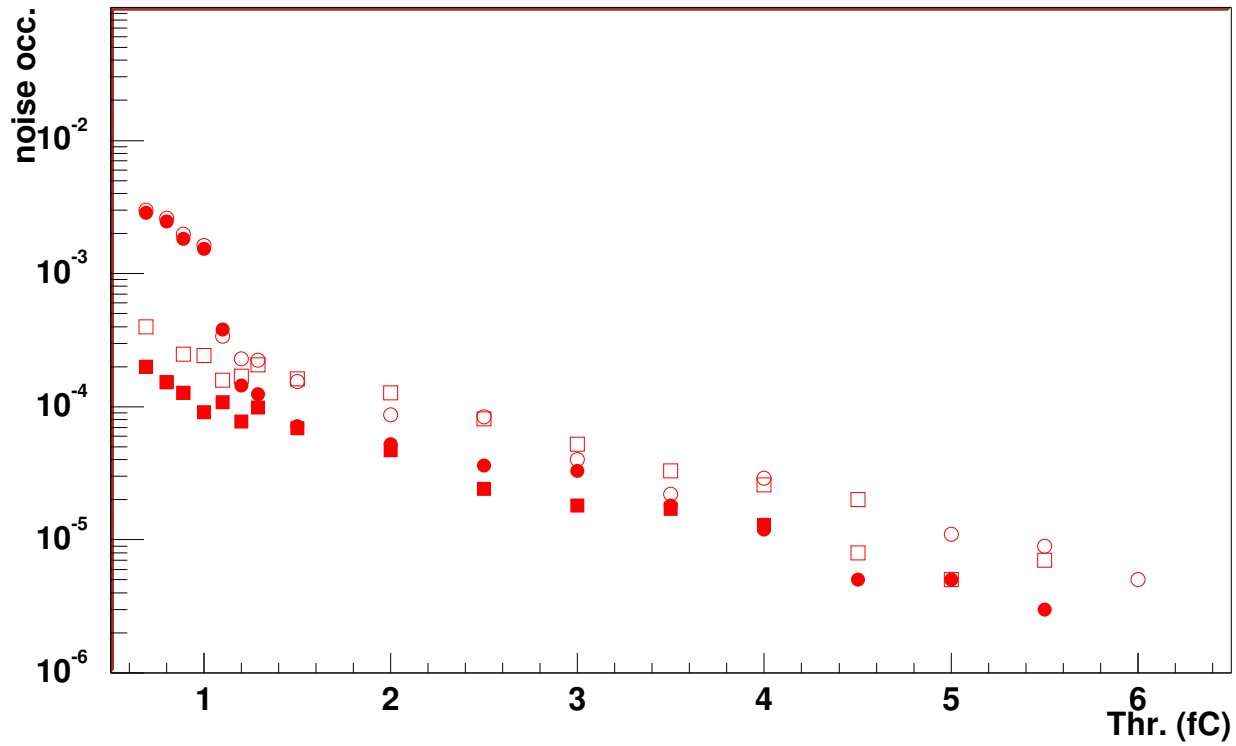


KEK3103: Scurve 160 V

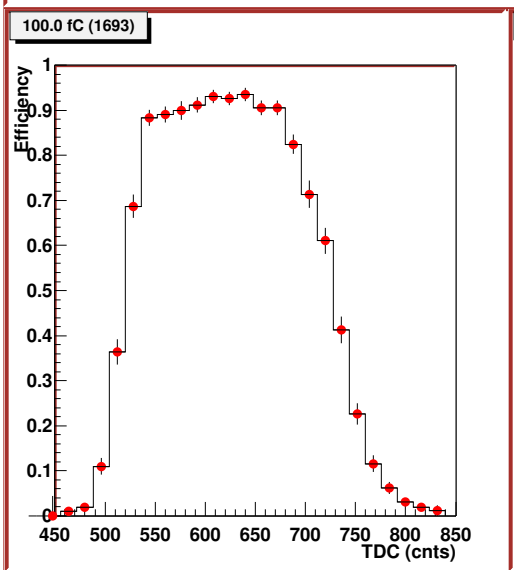
Efficiency

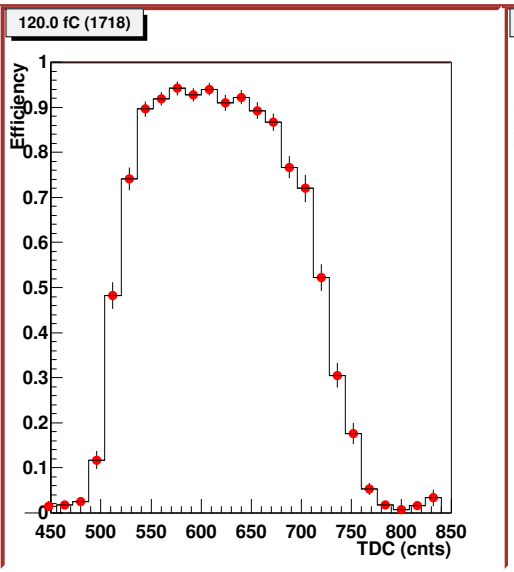


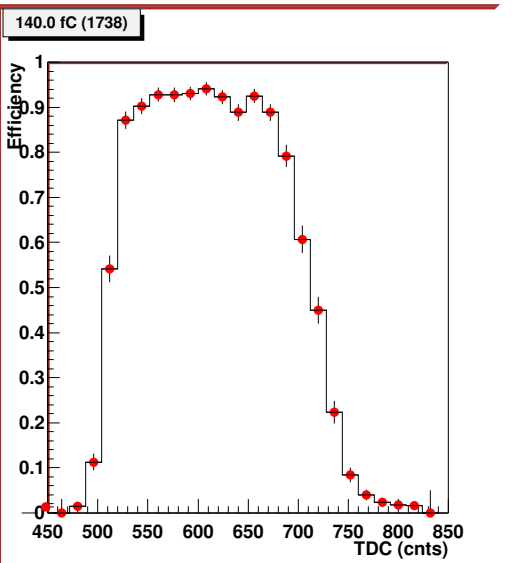
Noise occupancy

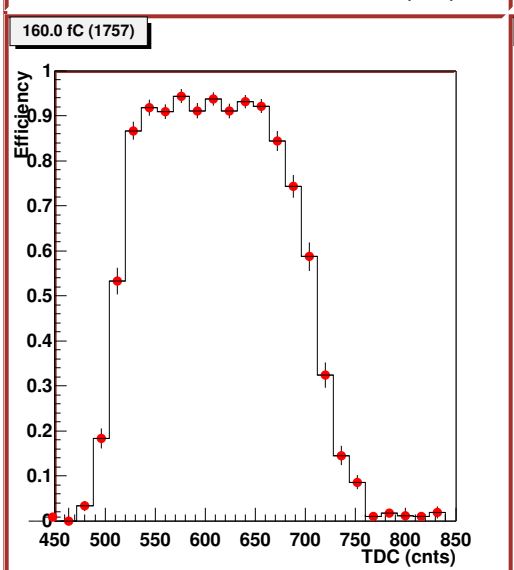


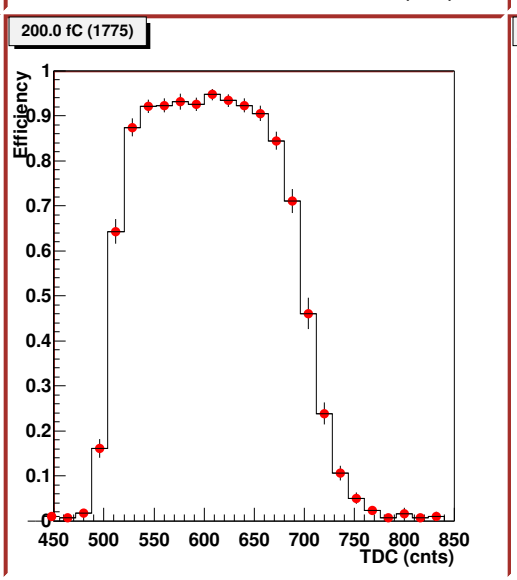
KEK3112-0 bias scan 1fC, max angle, B=1.65 T

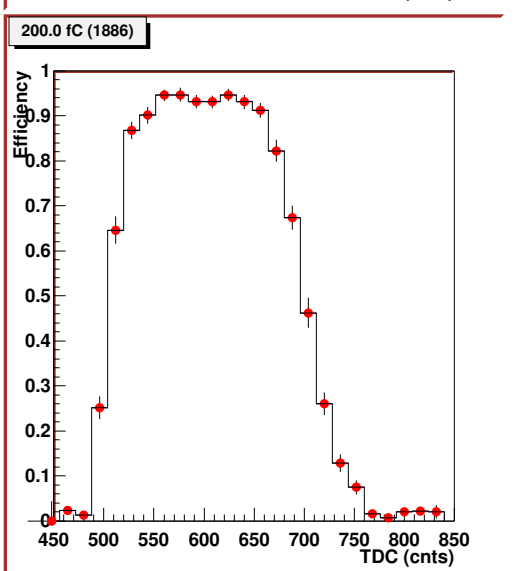


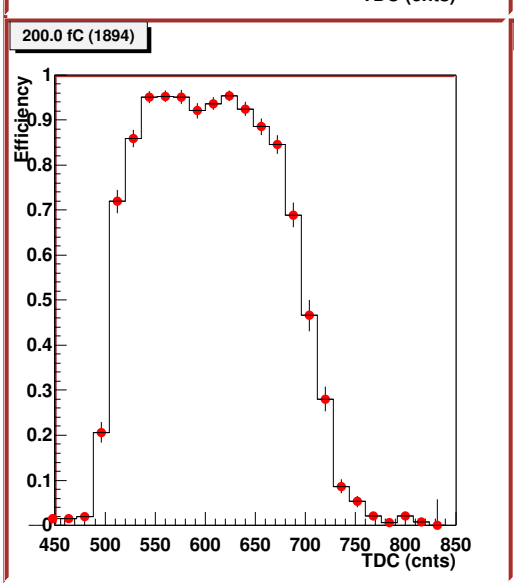


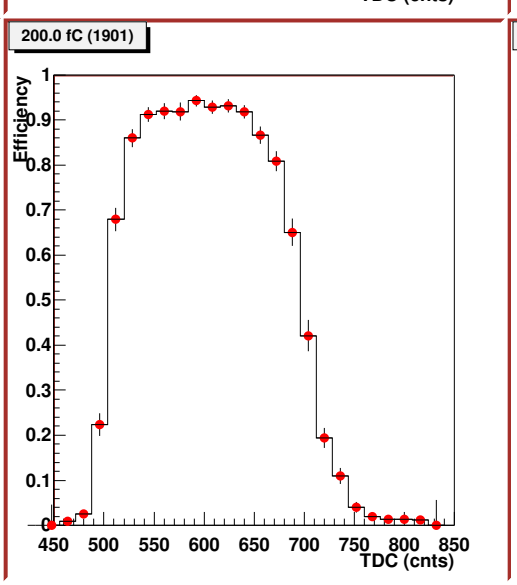


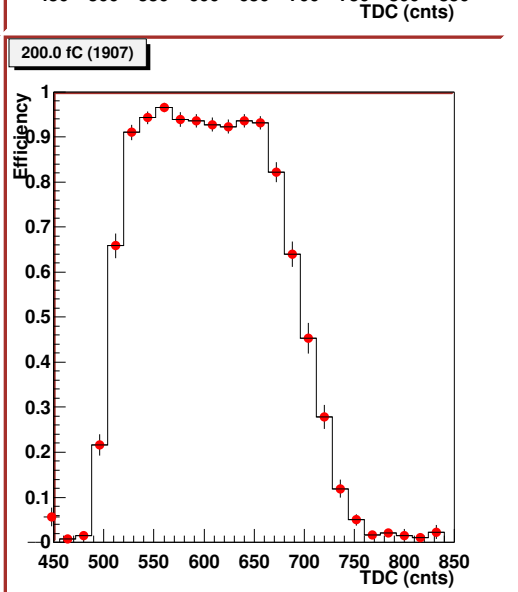




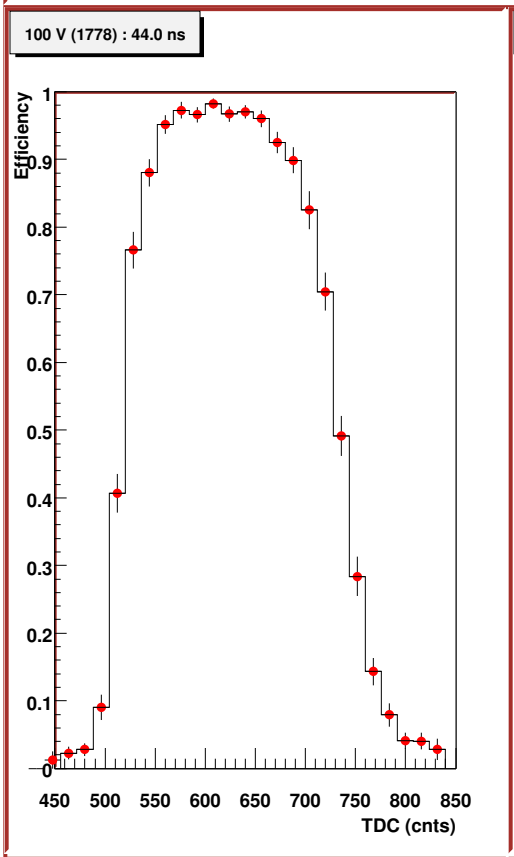


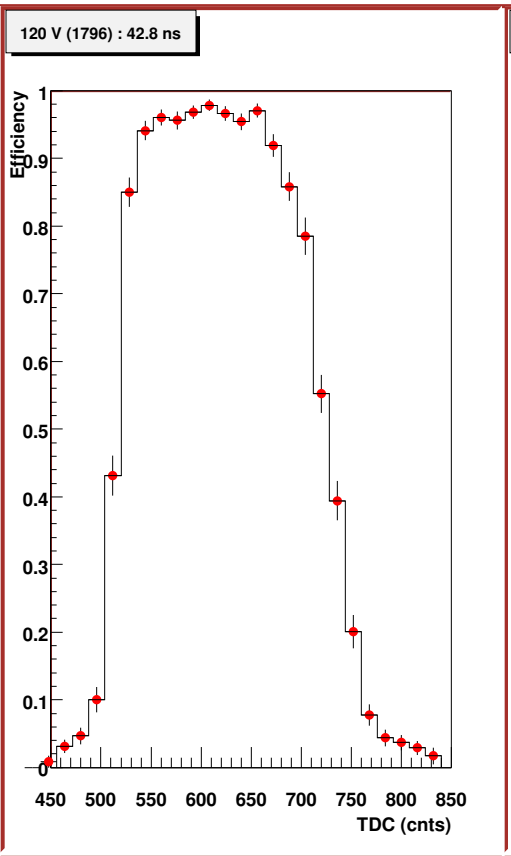


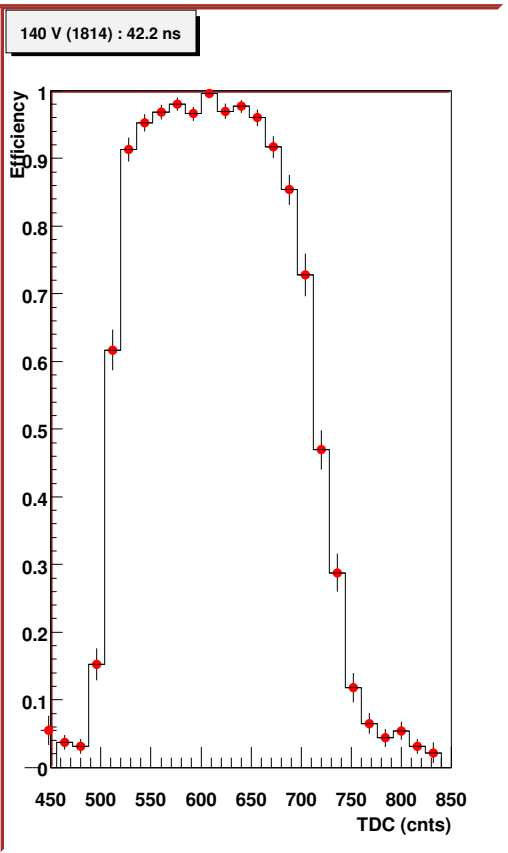


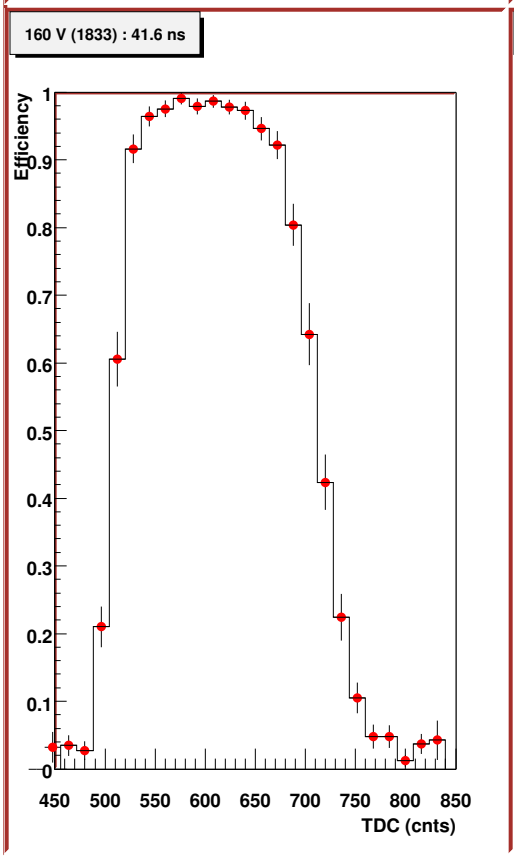


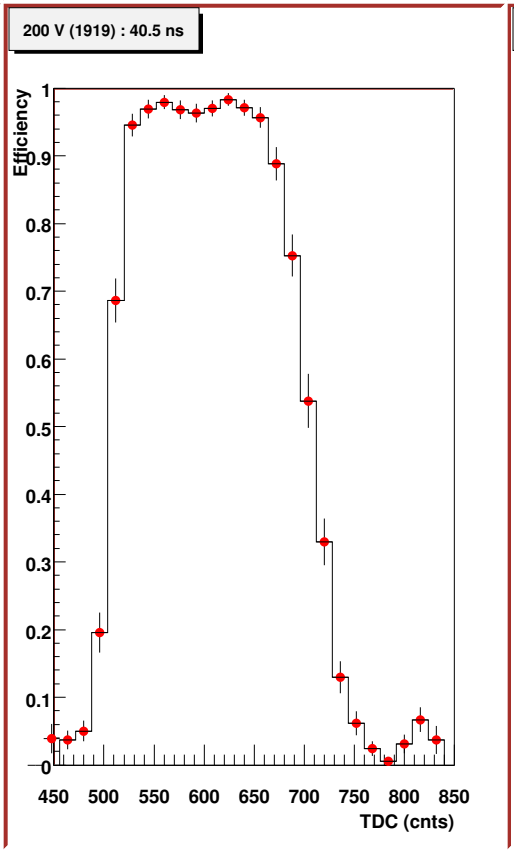
KEK3112-0 bias scan 1fC, max angle, no field

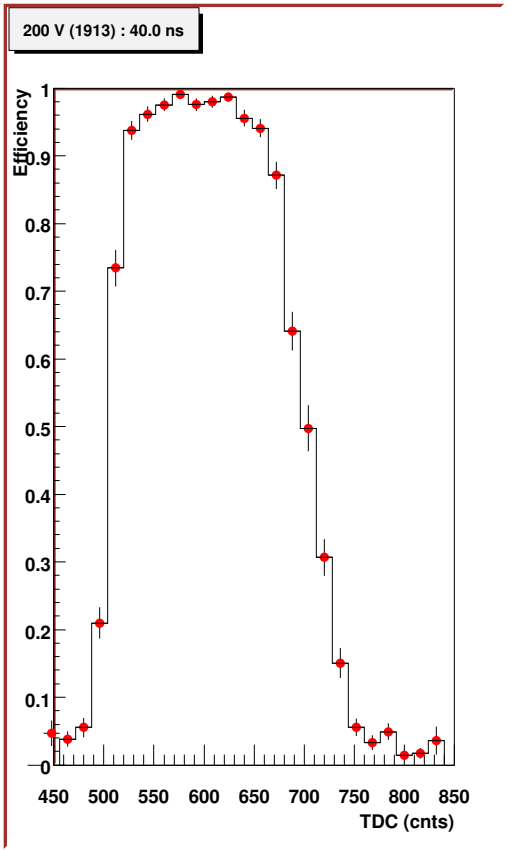






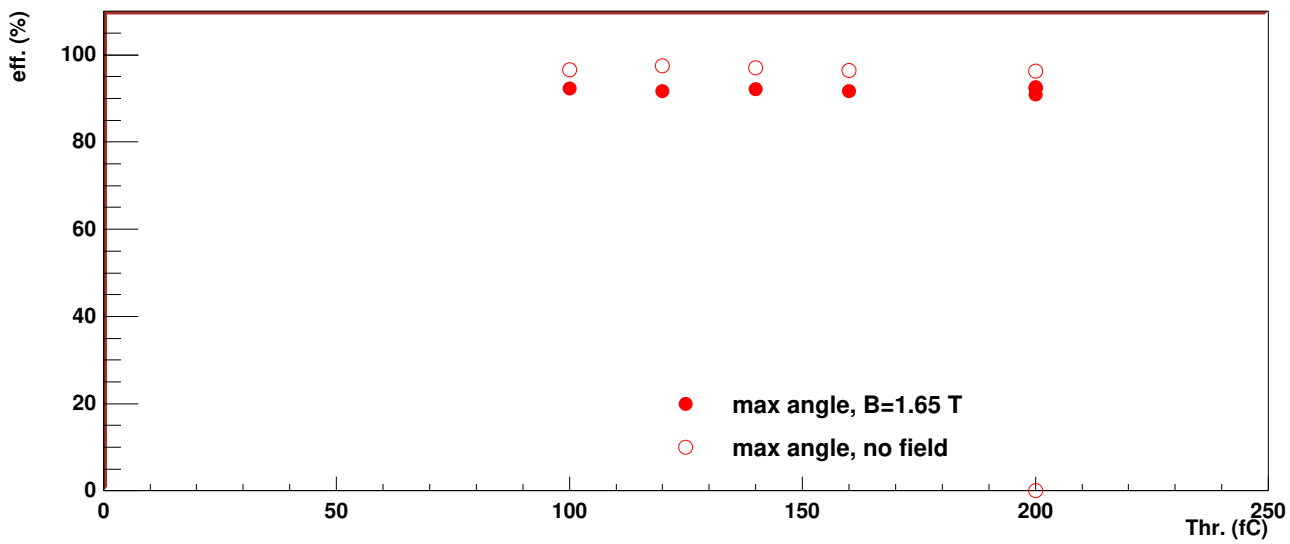




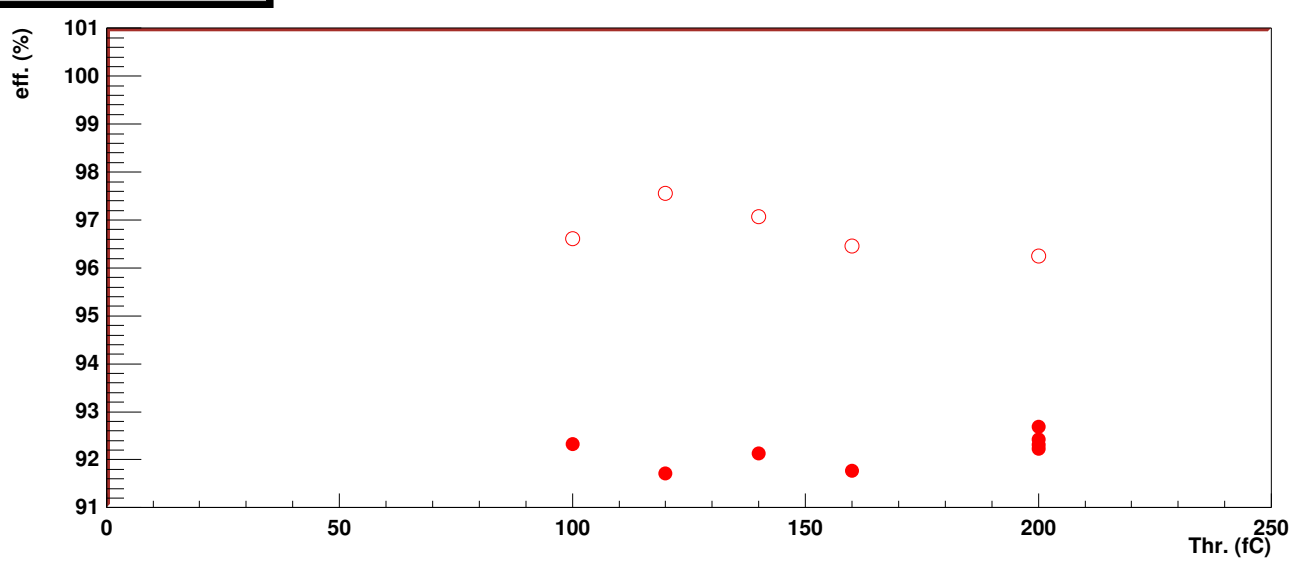


KEK3112: Bias scan 1 fC, max angle

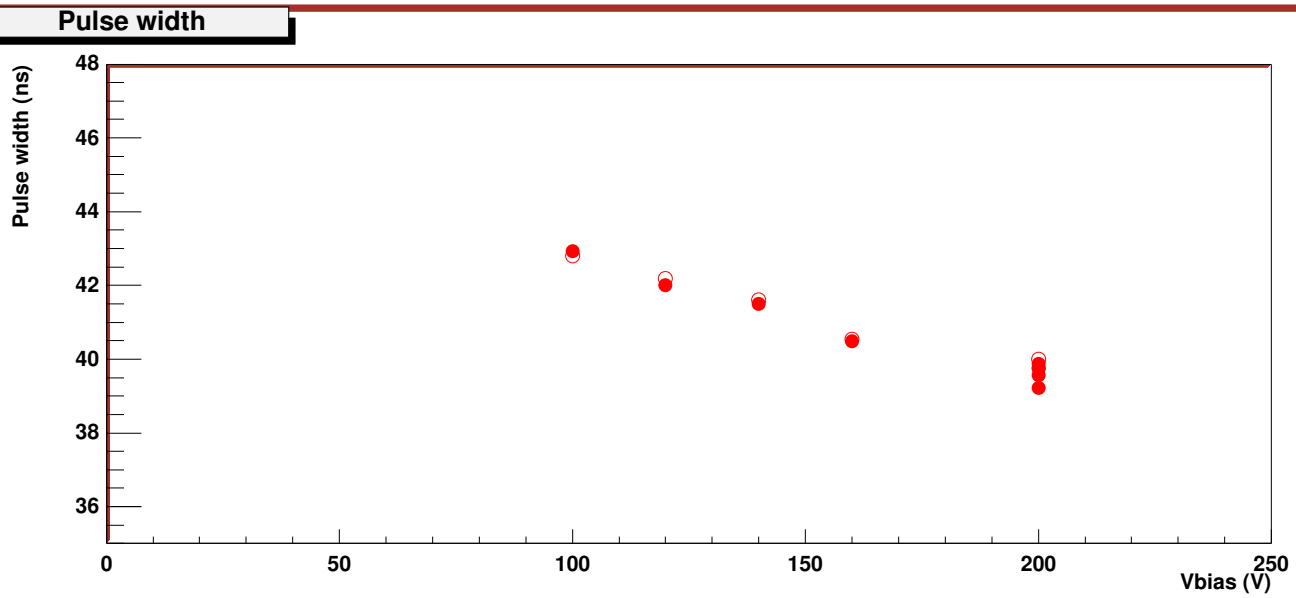
Efficiency



Efficiency

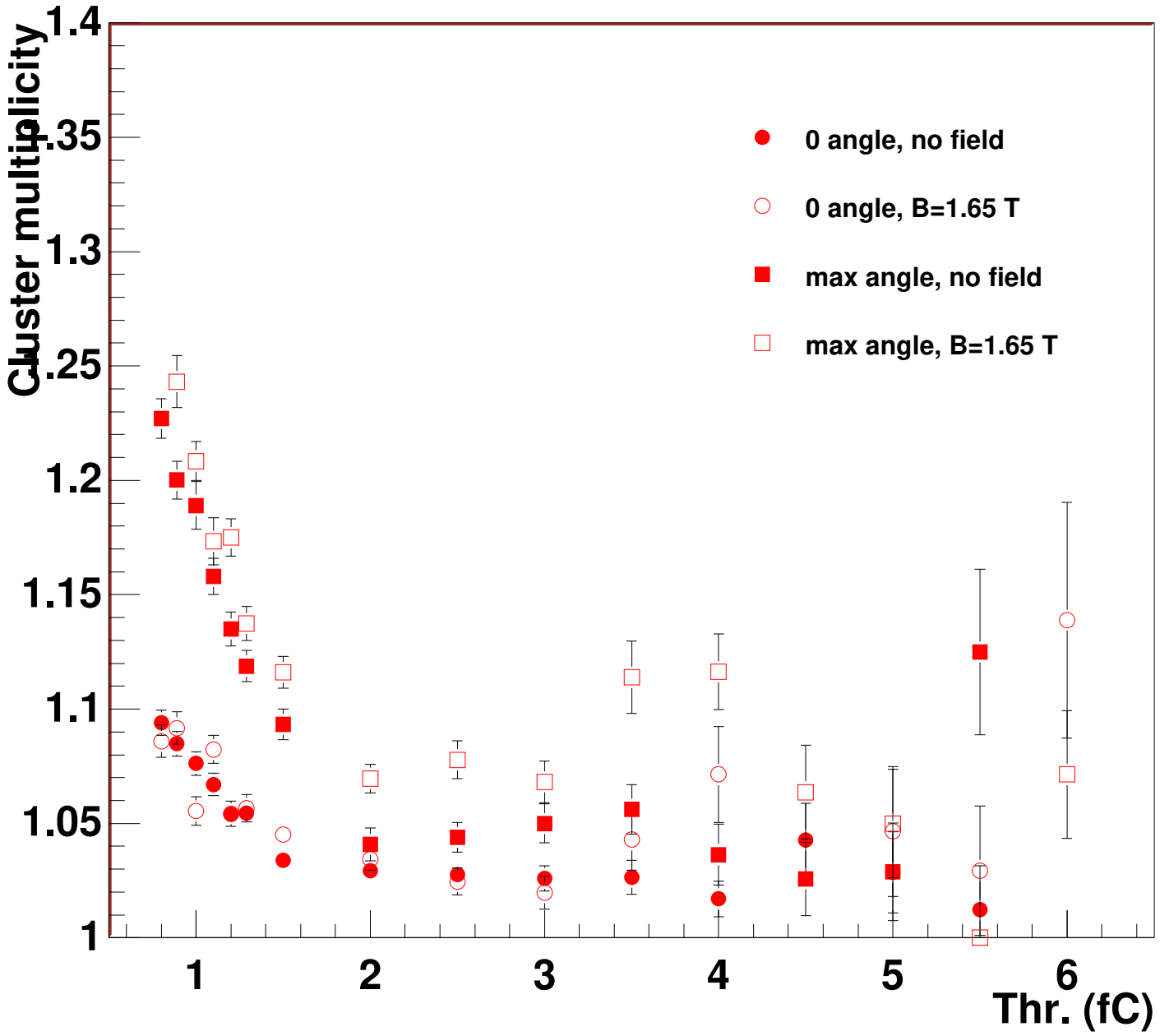


Pulse width

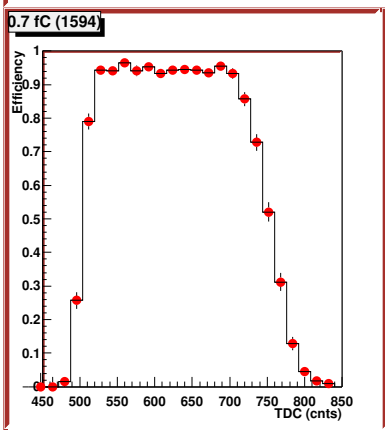


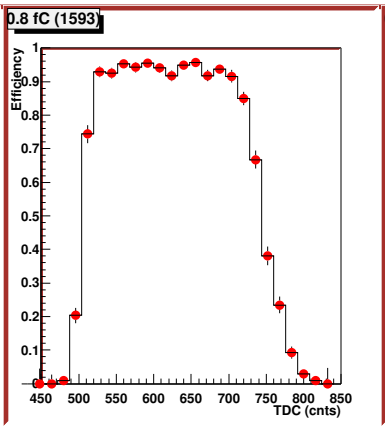
KEK3112: Av. cluster multiplicity 160 V

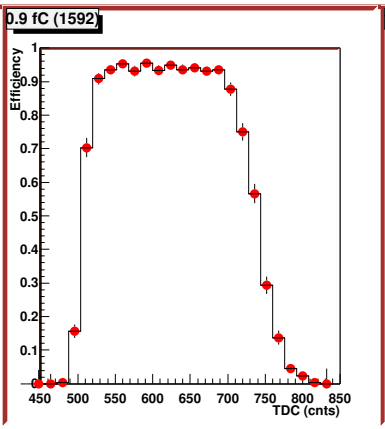
efficient clusters

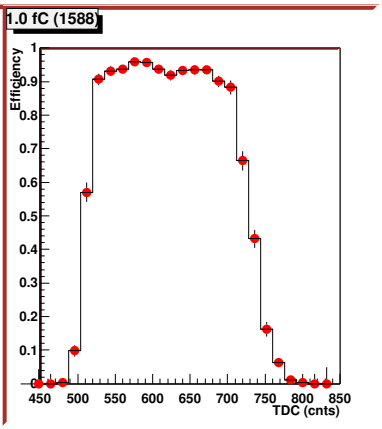


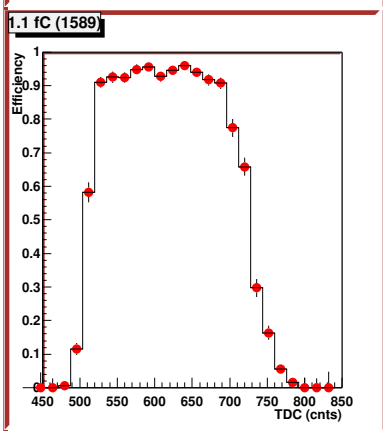
KEK3112-0 threshold scan 160 V, 0 angle, no field

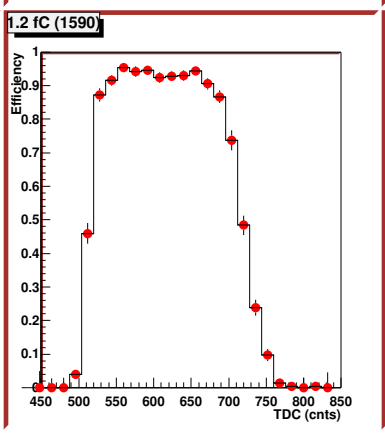


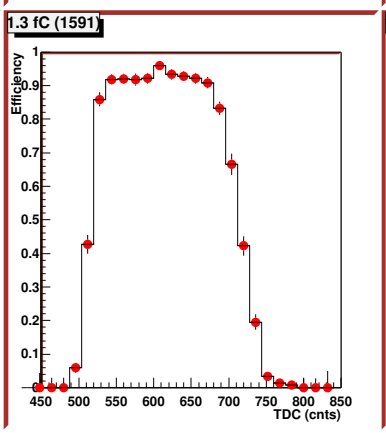


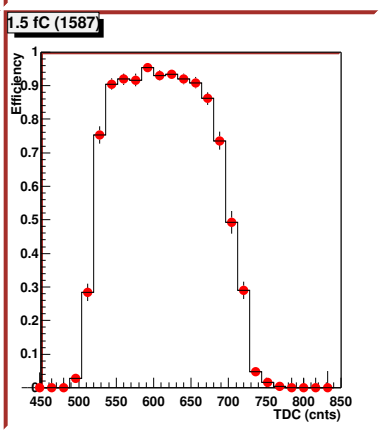


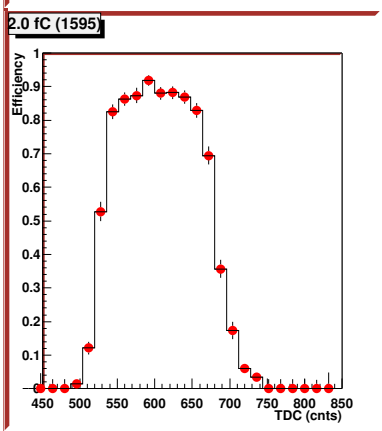


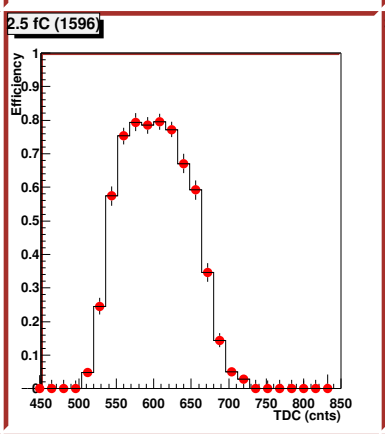


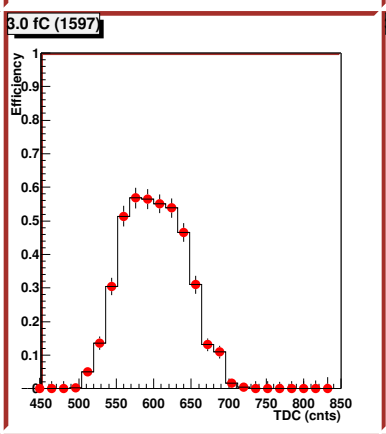


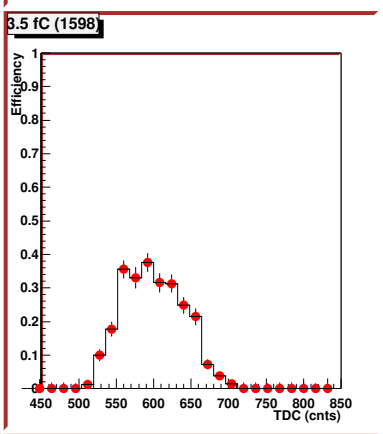


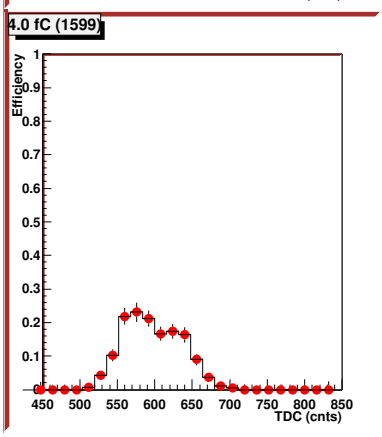


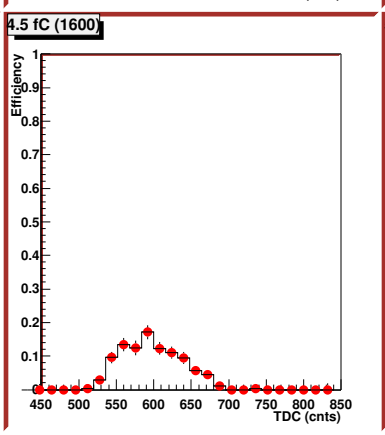


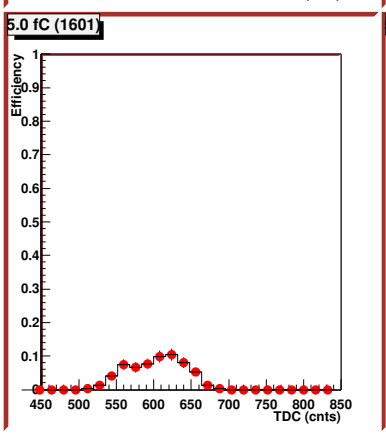


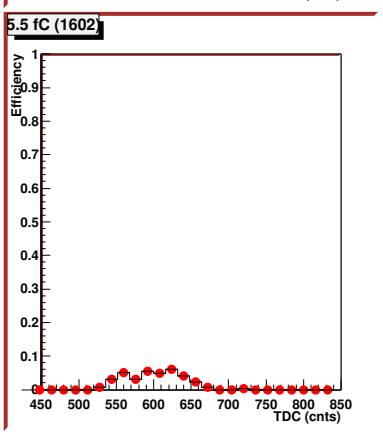




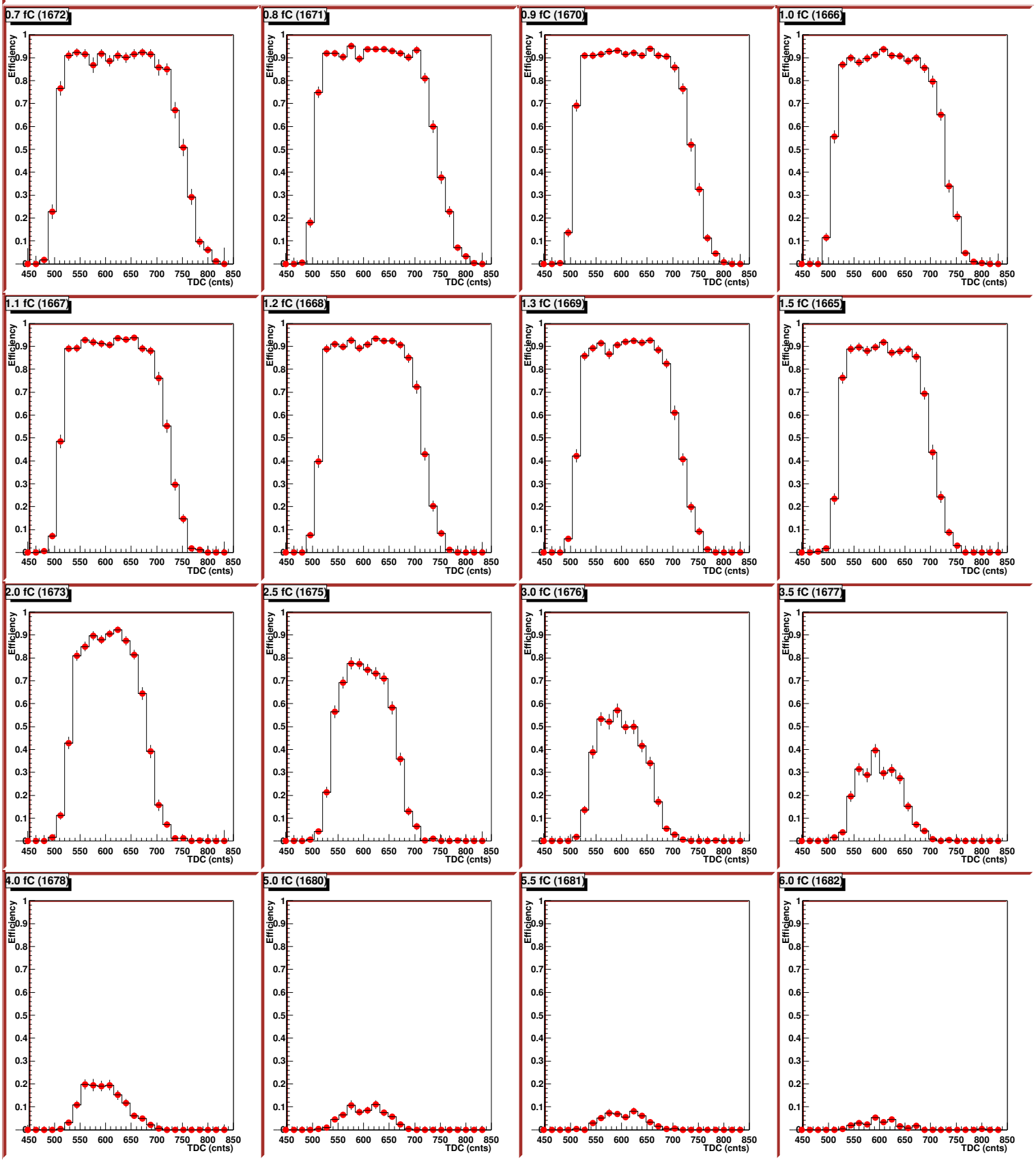




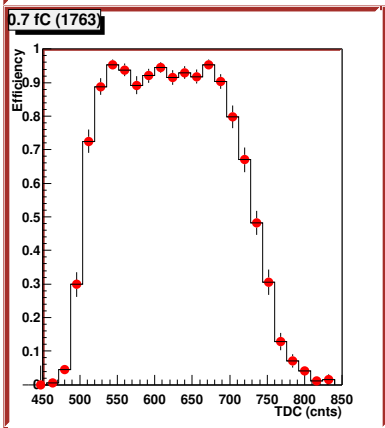


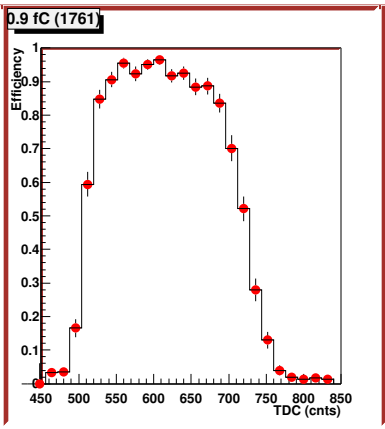


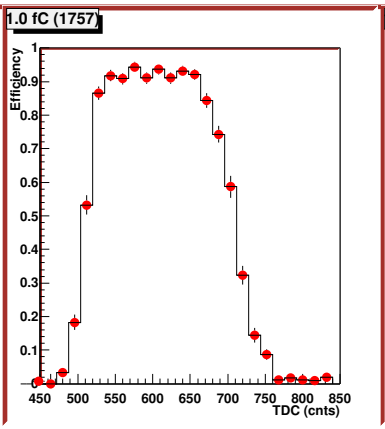
KEK3112-0 threshold scan 160 V, 0 angle, B=1.65 T

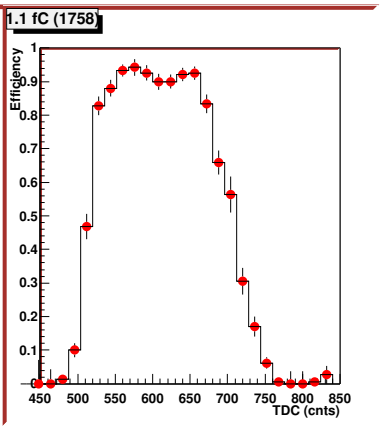


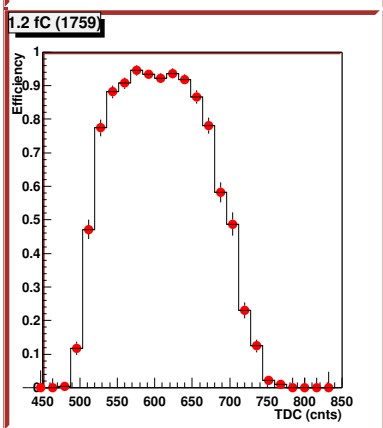
KEK3112-0 threshold scan 160 V, max angle, B=1.65 T

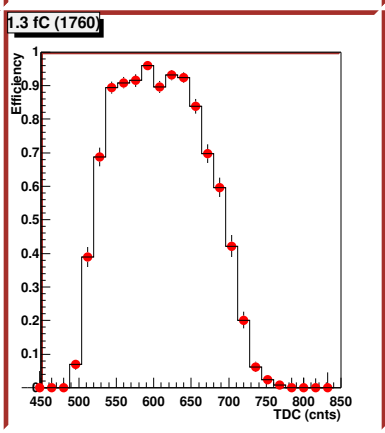


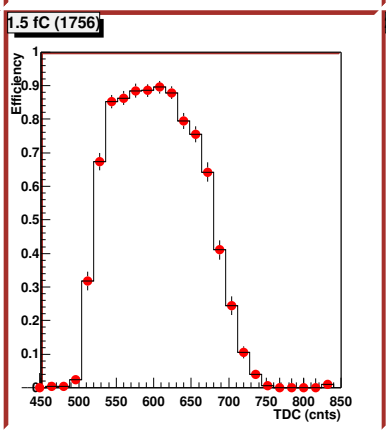


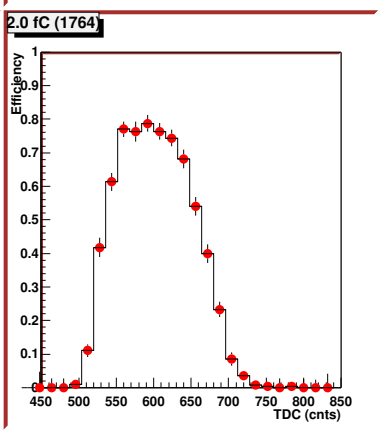


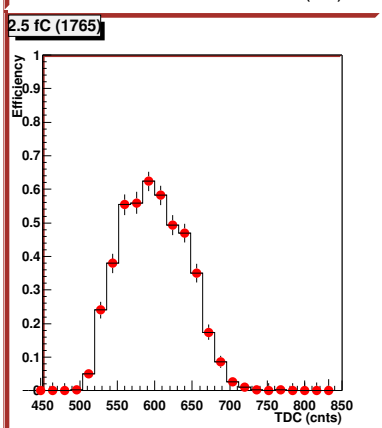


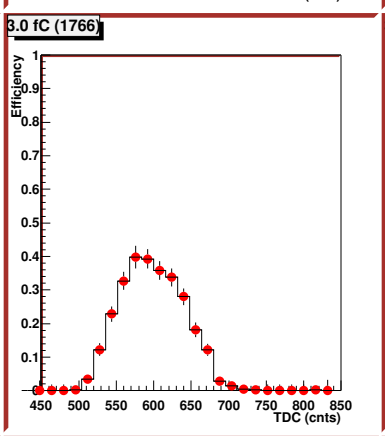


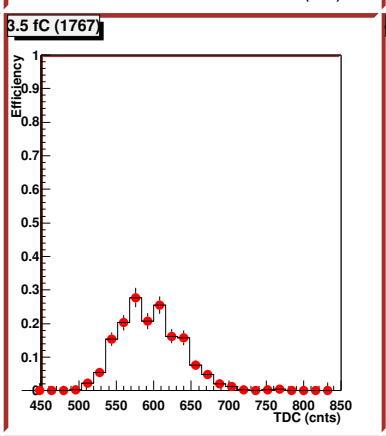


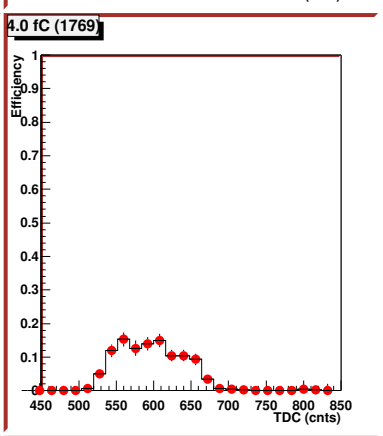


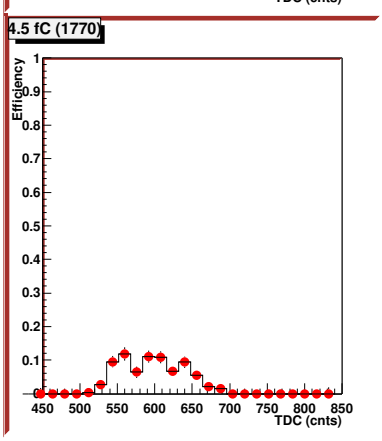


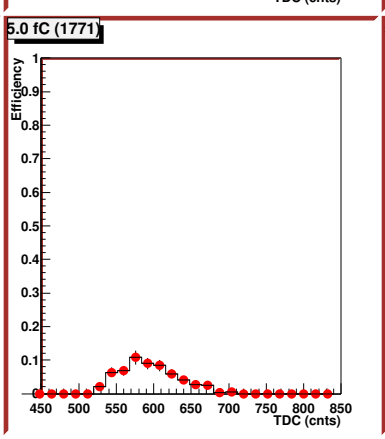


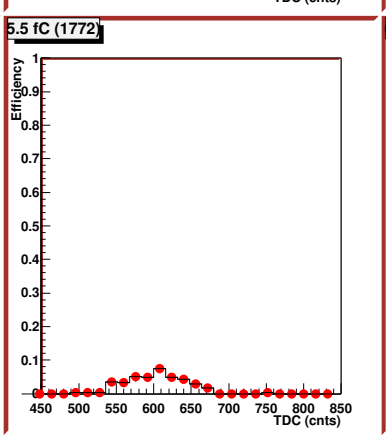


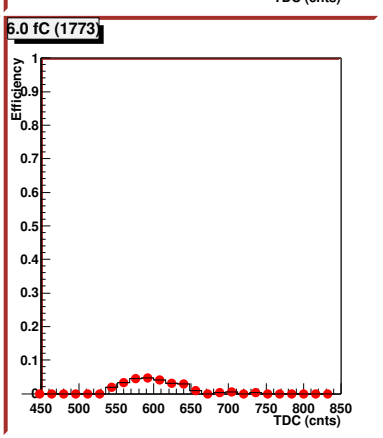




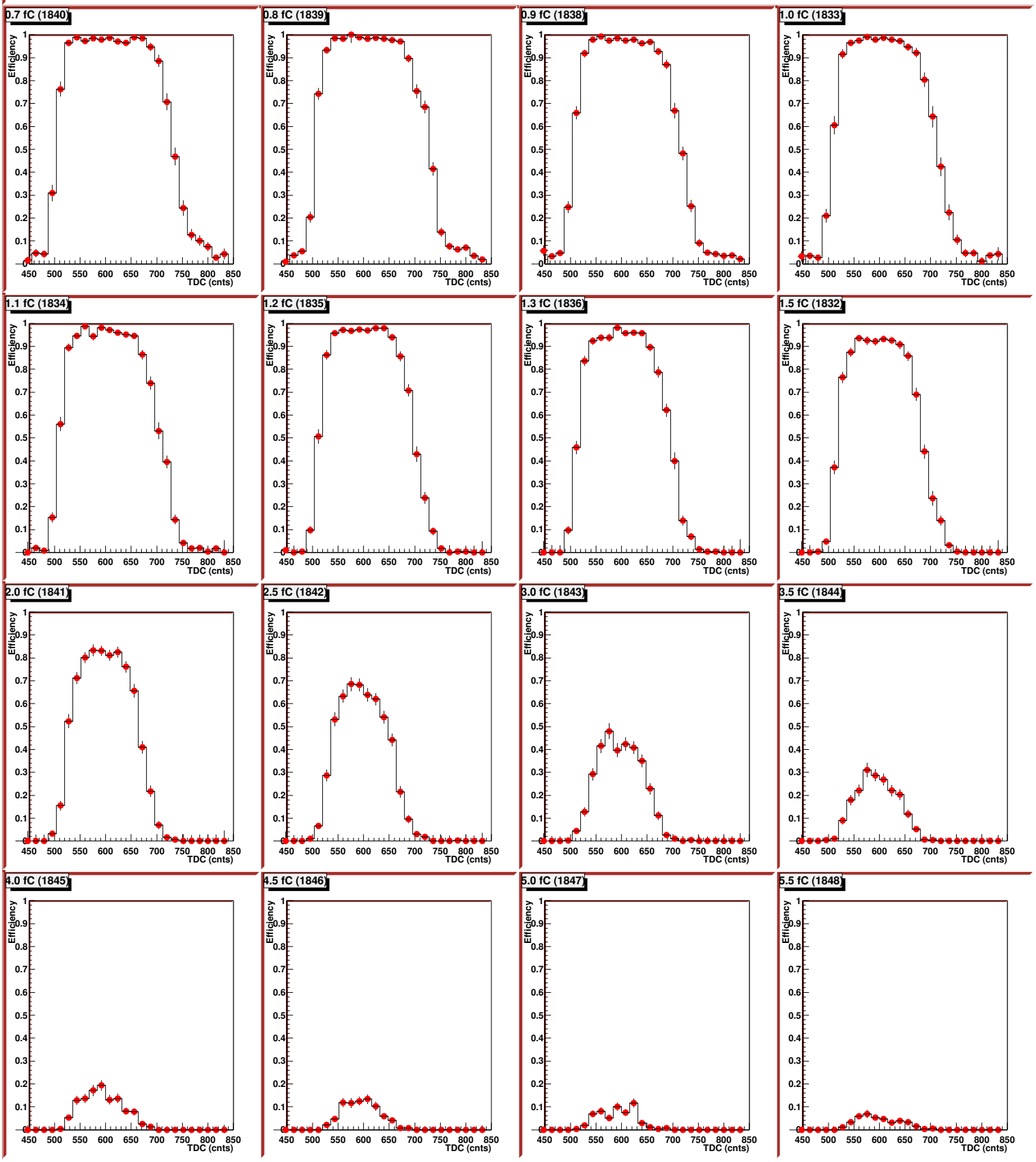






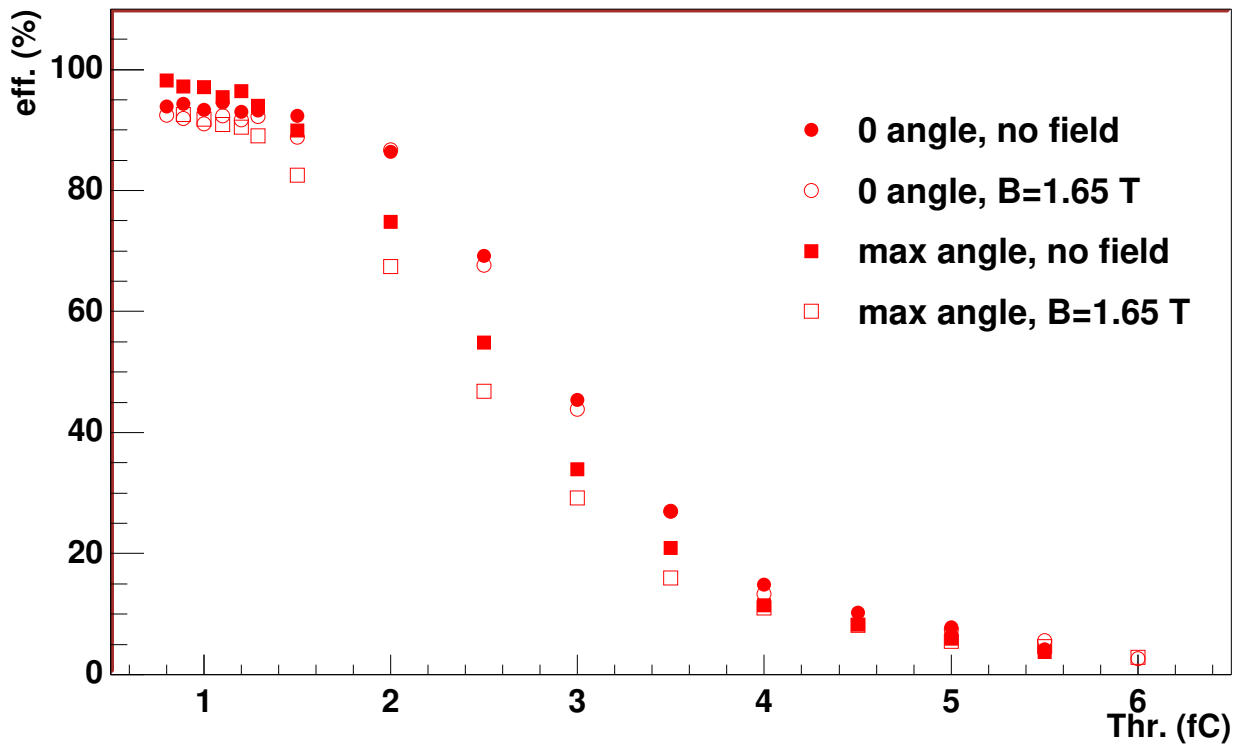


KEK3112-0 threshold scan 160 V, max angle, no field

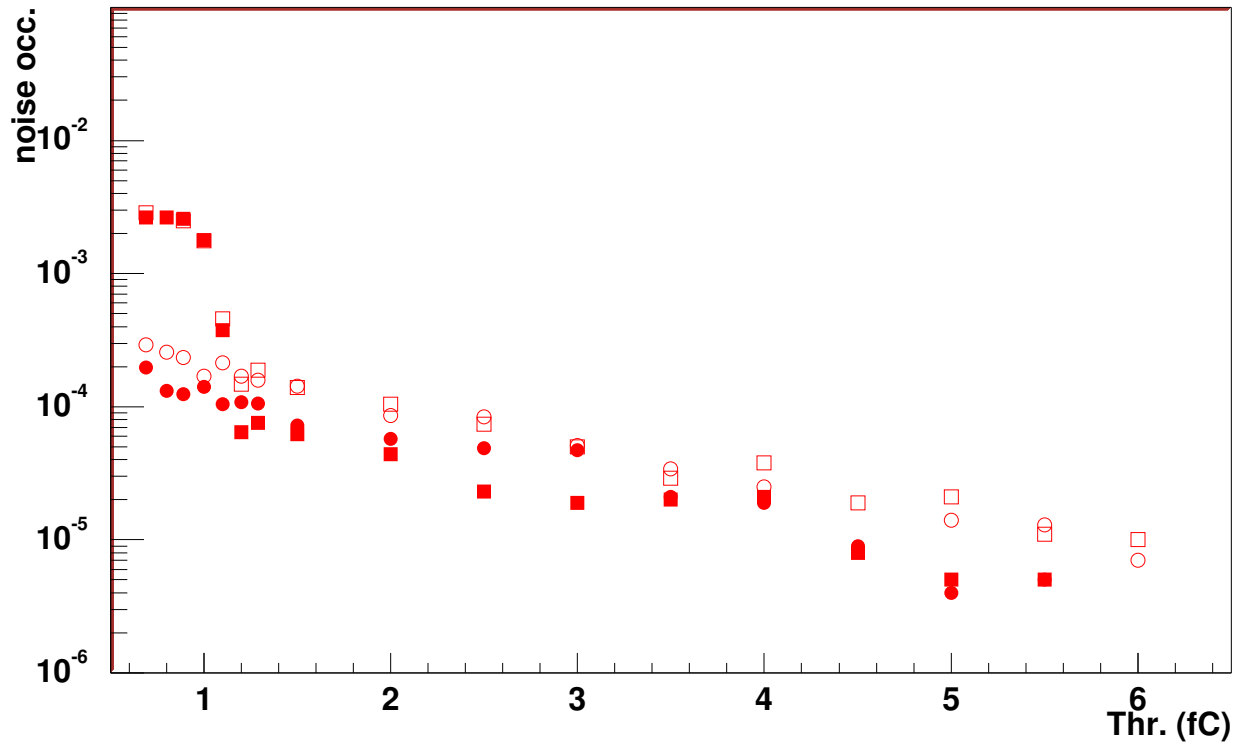


KEK3112: Scurve 160 V

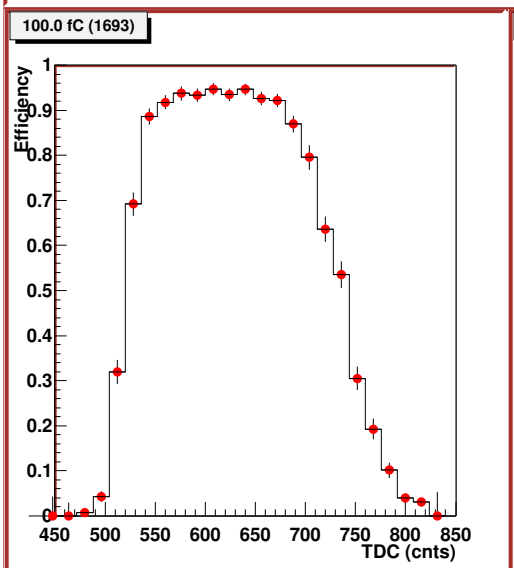
Efficiency

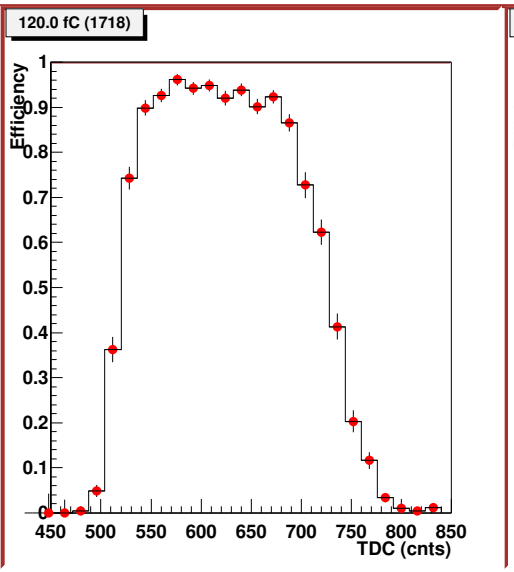


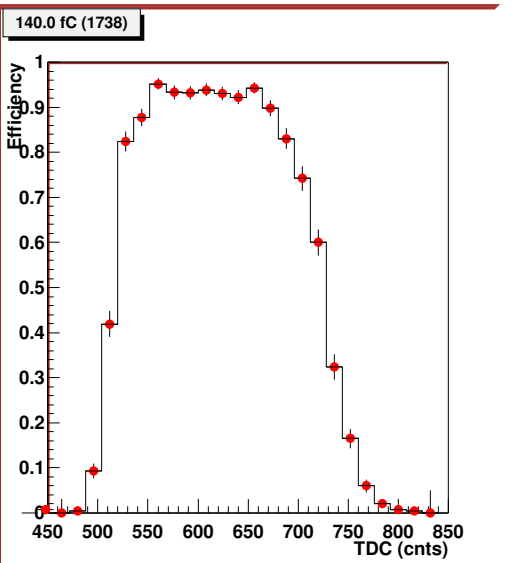
Noise occupancy

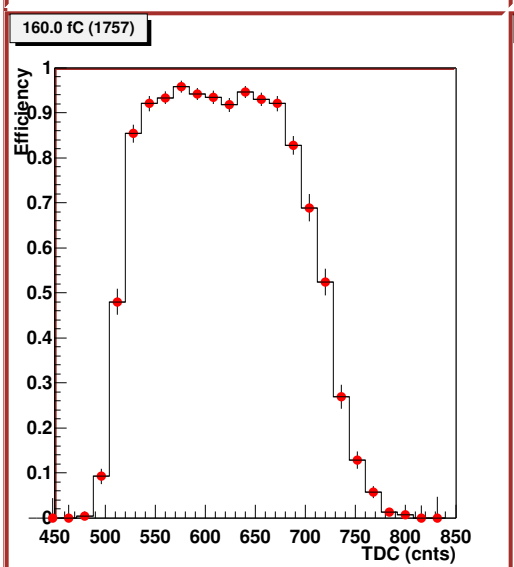


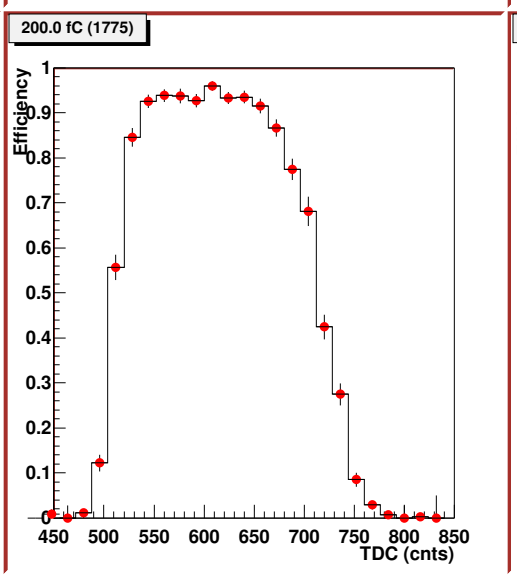
RLT5-0 bias scan 1 fC, max angle, B=1.65 T

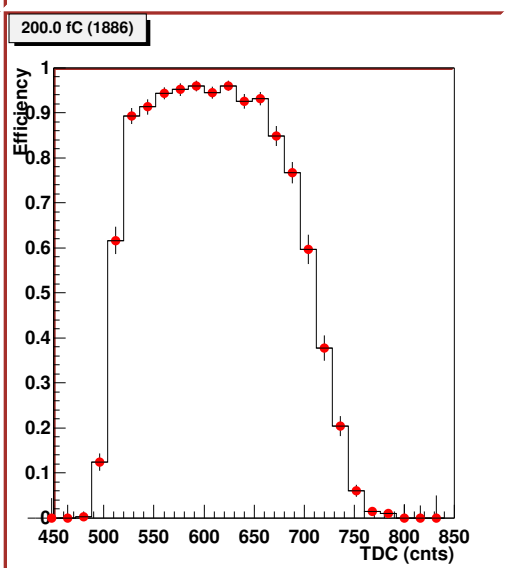


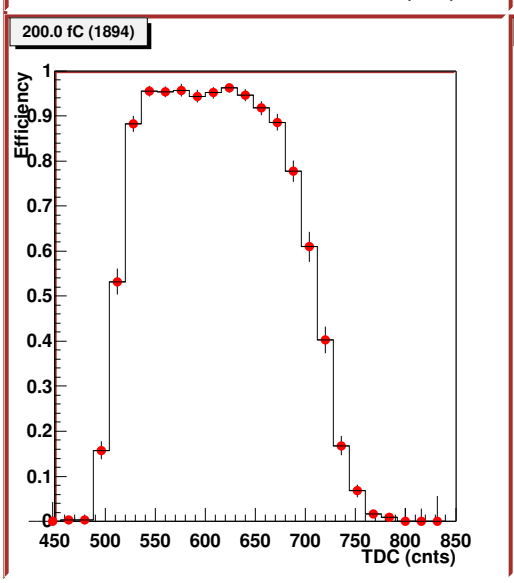


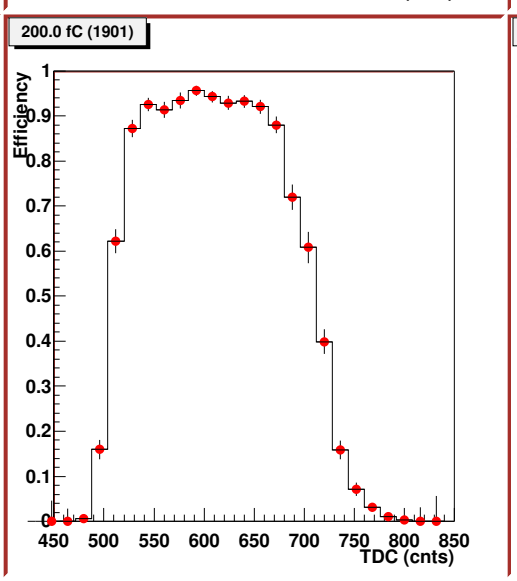


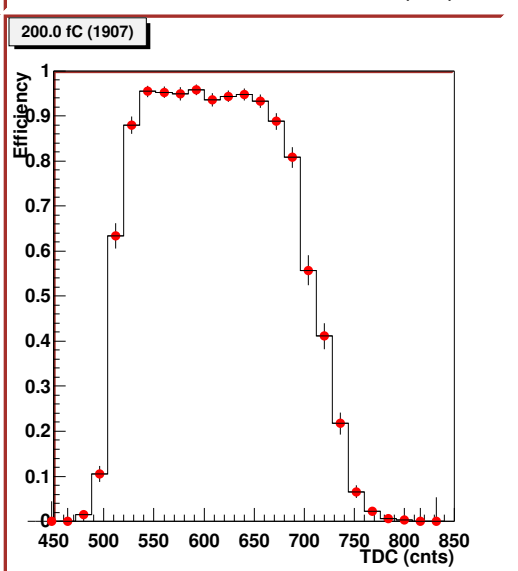






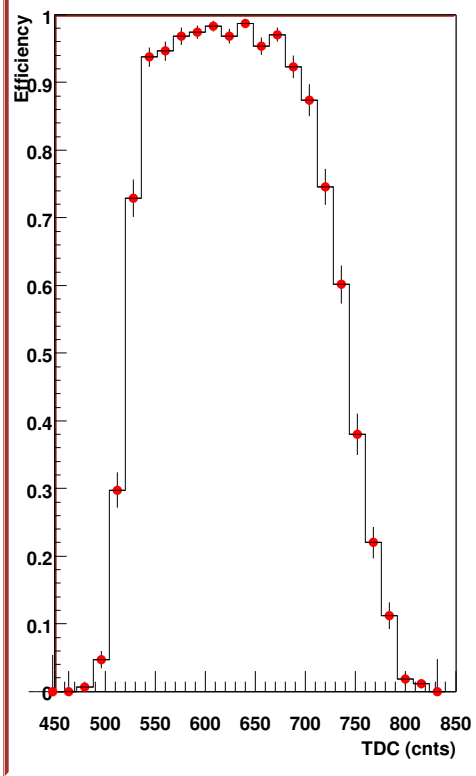




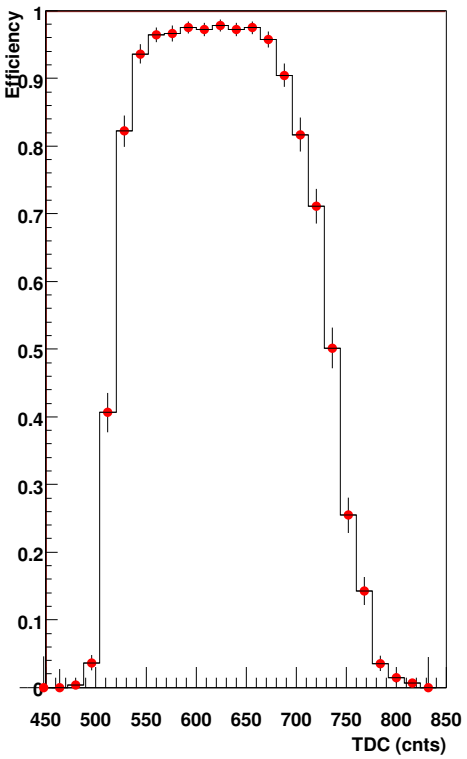


RLT5-0 bias scan 1 fC, max angle, no field

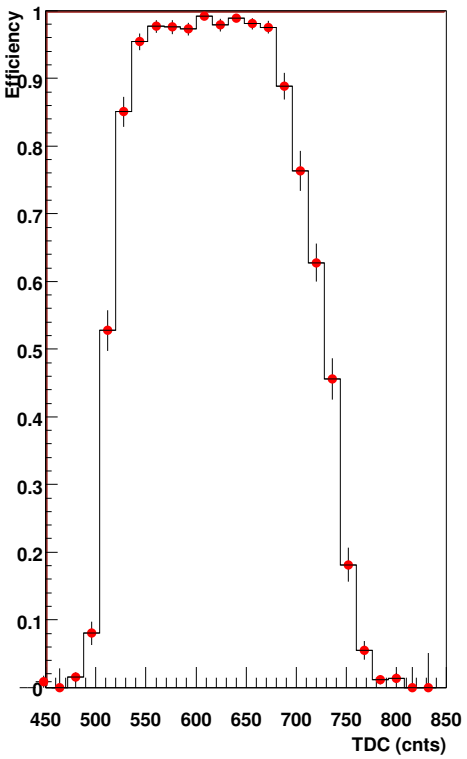
100 V (1778) : 44.8 ns



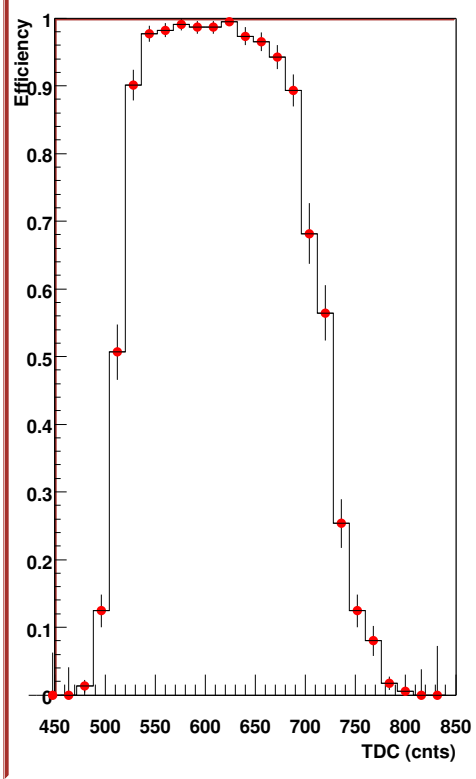
120 V (1796) : 44.0 ns



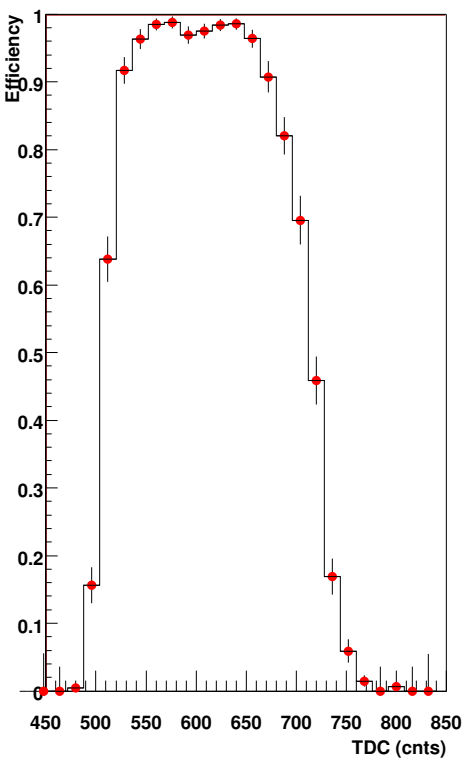
140 V (1814) : 43.1 ns



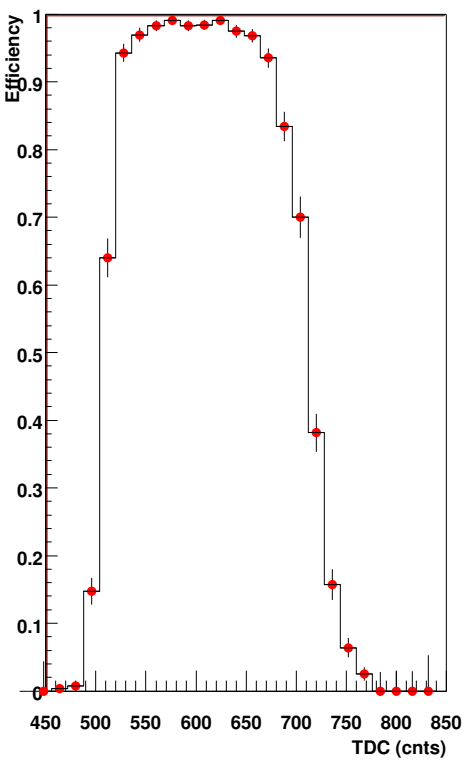
160 V (1833) : 42.1 ns



200 V (1919) : 41.4 ns

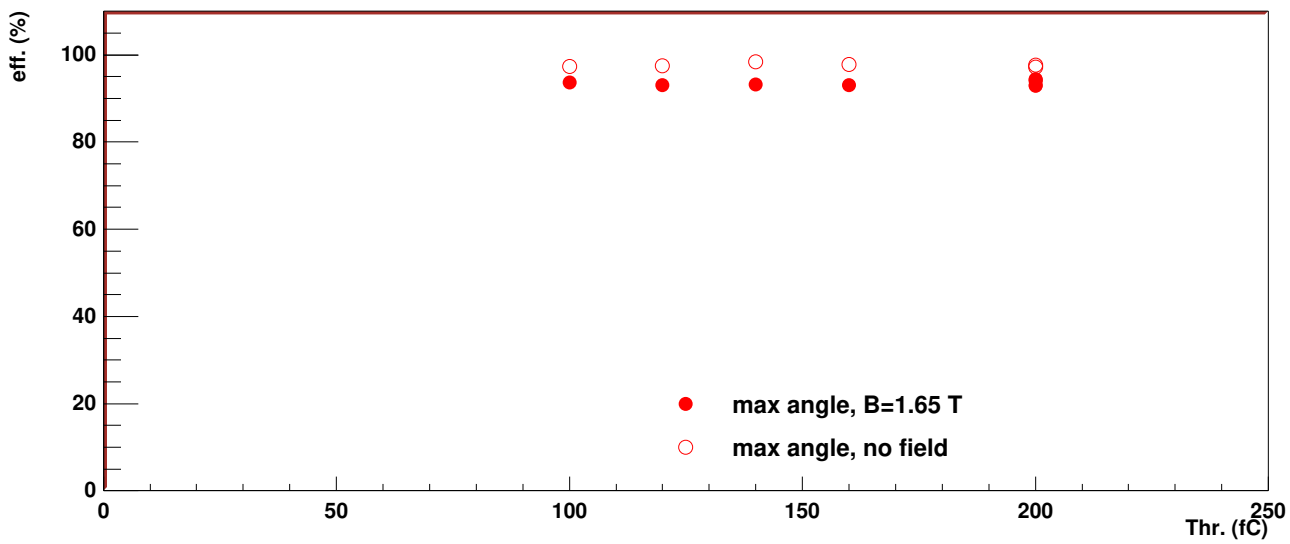


200 V (1913) : 41.2 ns

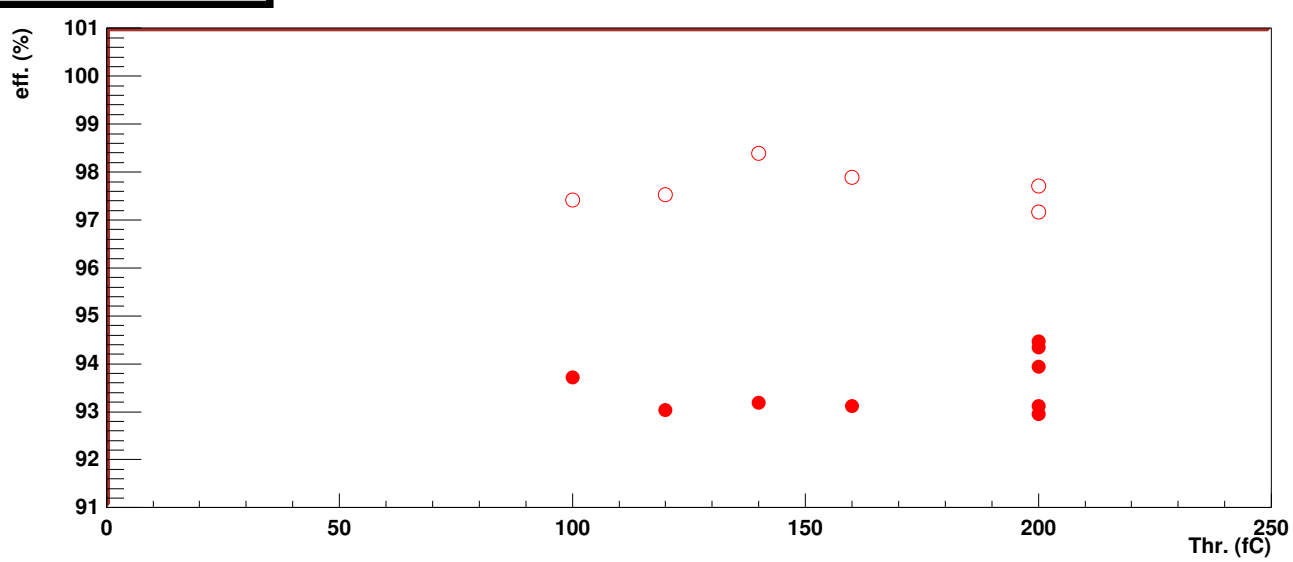


RLT5: Bias scan 1 fC, max angle

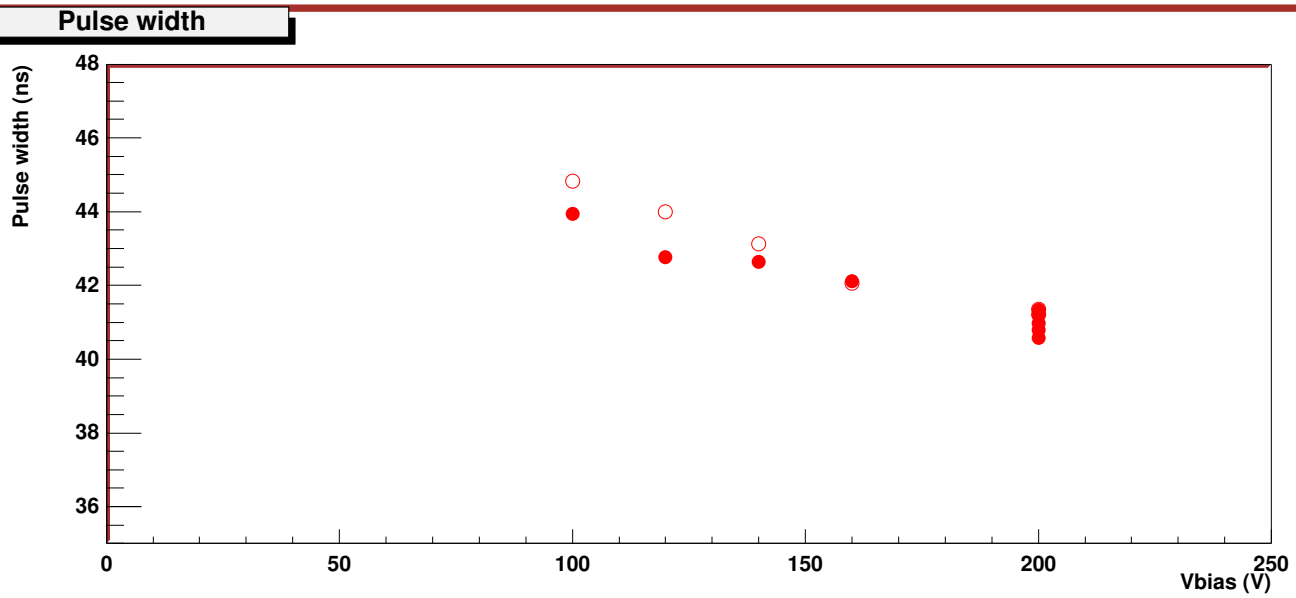
Efficiency



Efficiency

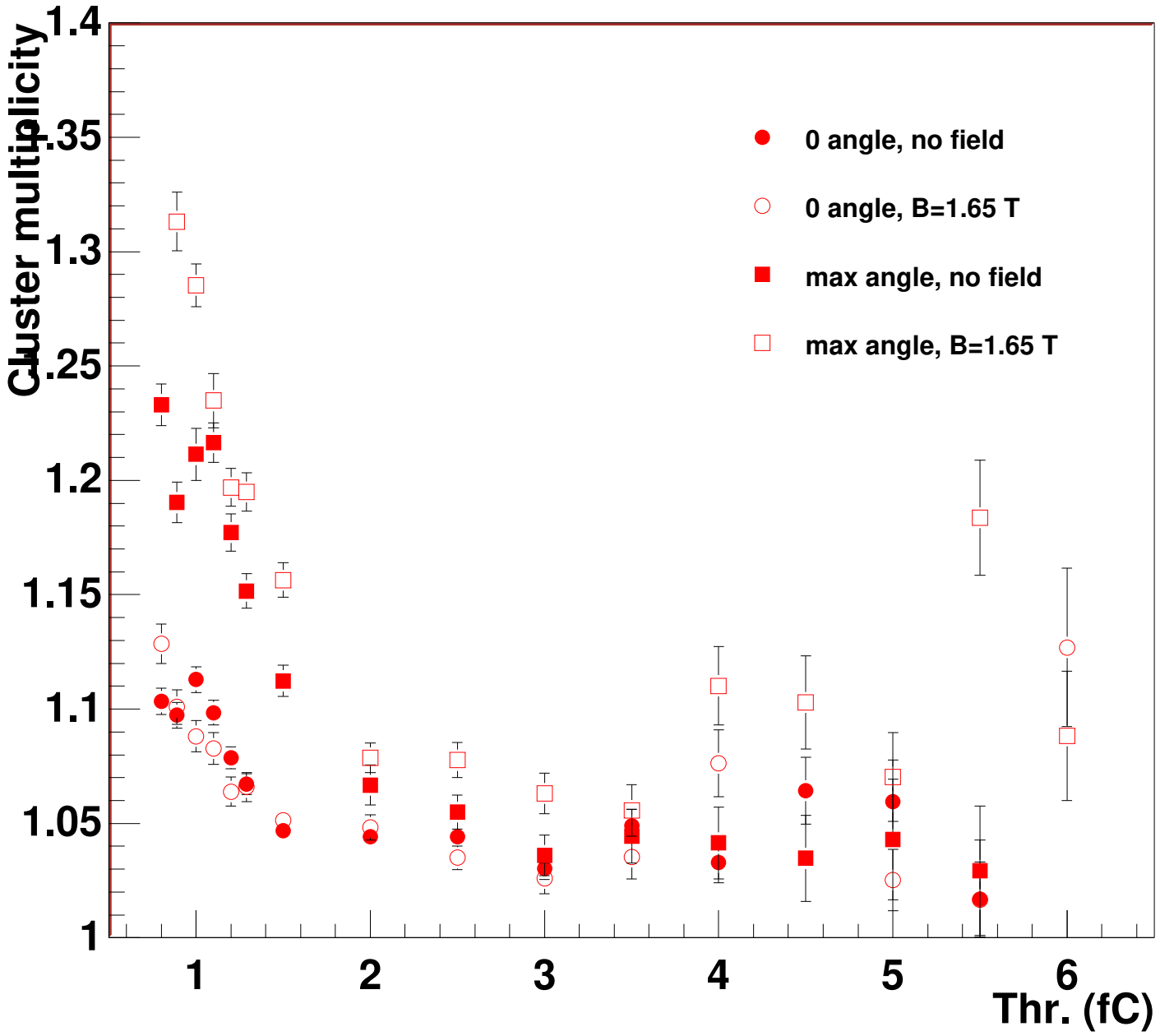


Pulse width

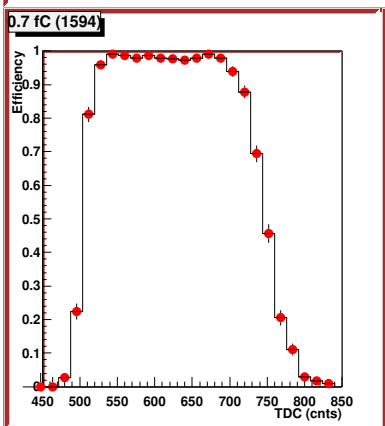


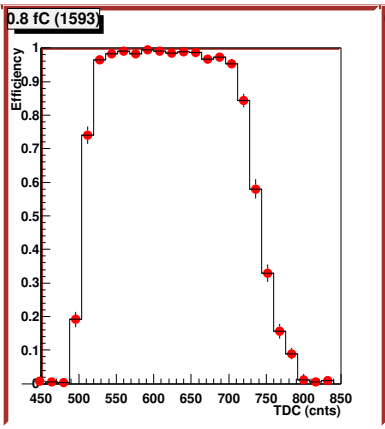
RLT5: Av. cluster multiplicity 160 V

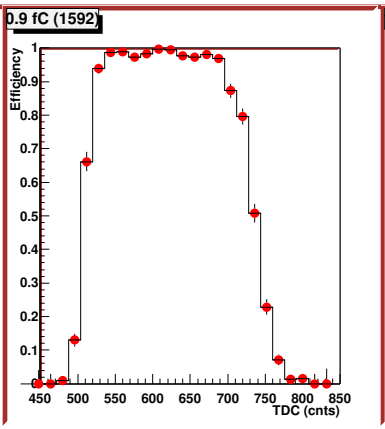
efficient clusters

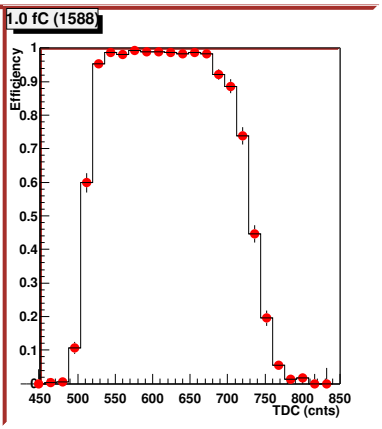


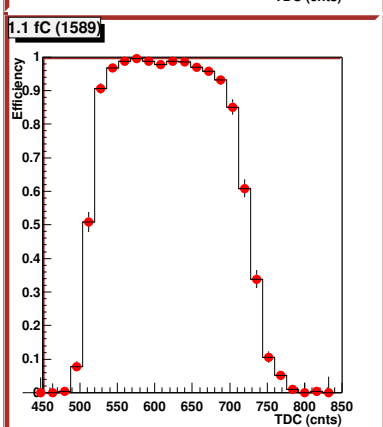
RLT5-0 threshold scan 160 V, 0 angle, no field

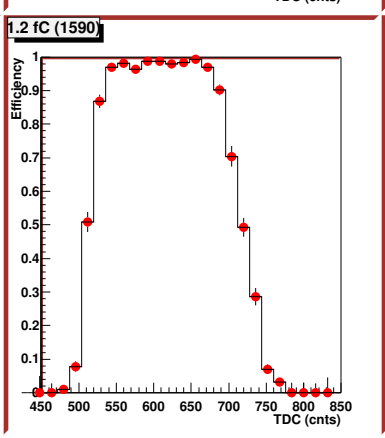


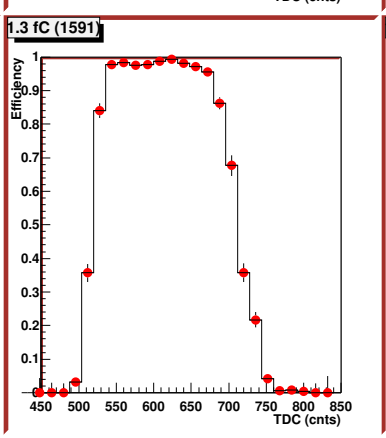


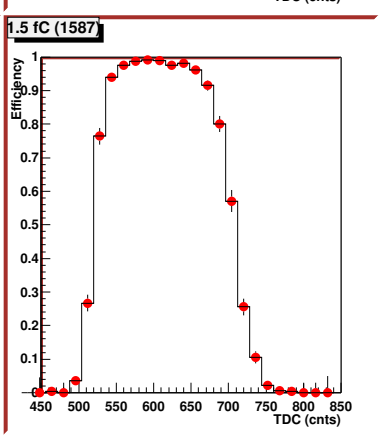


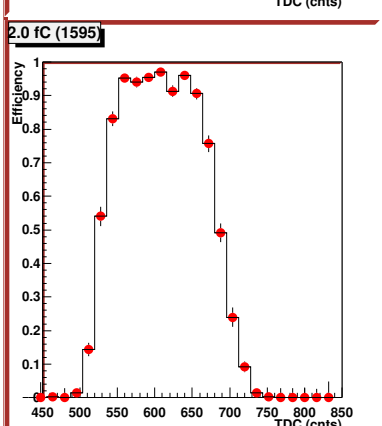


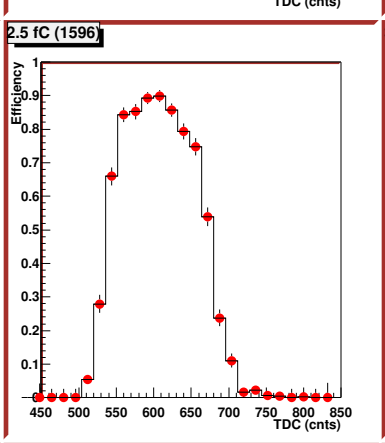


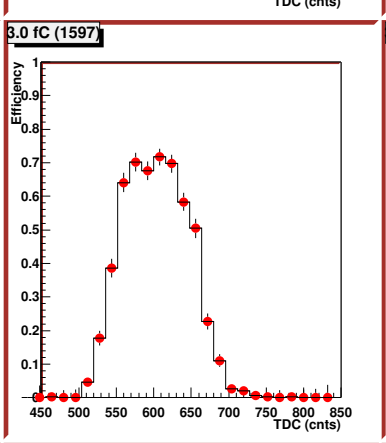


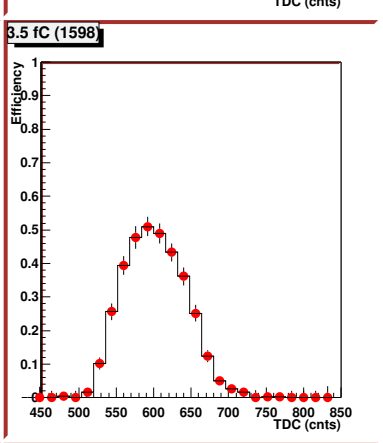


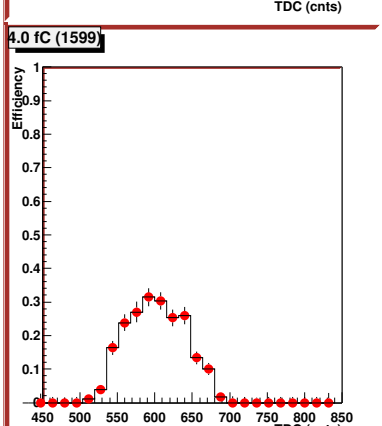


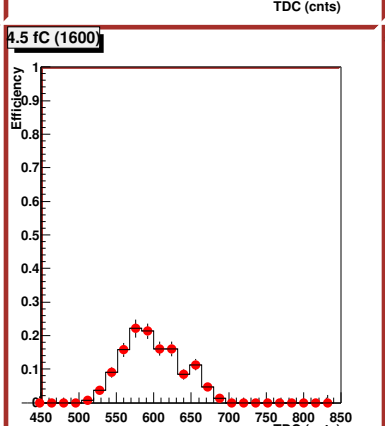


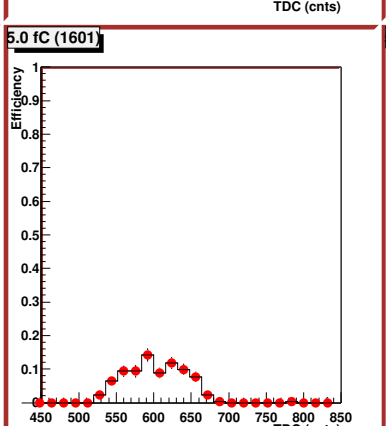


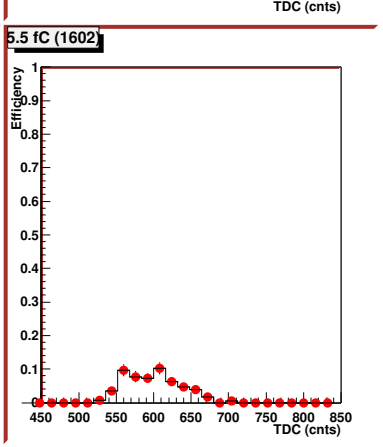




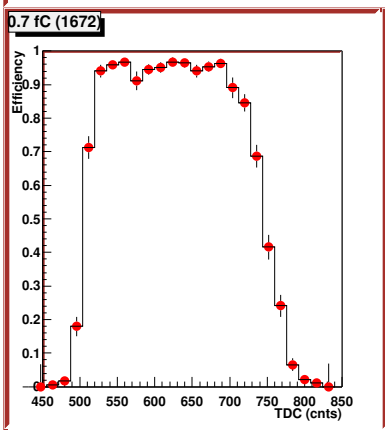


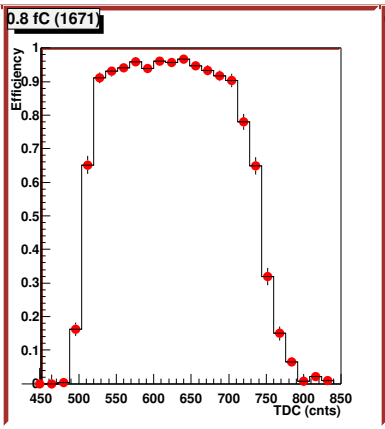


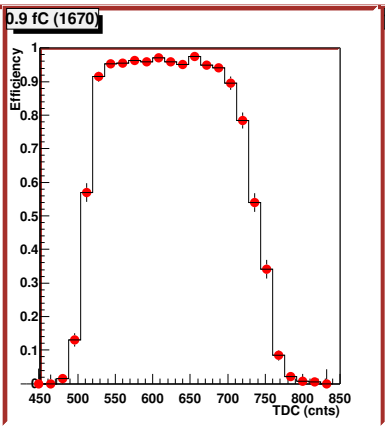


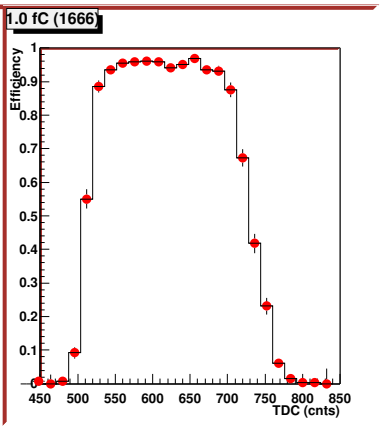


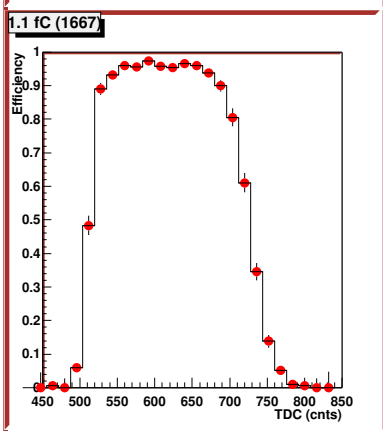
RLT5-0 threshold scan 160 V, 0 angle, B=1.65 T

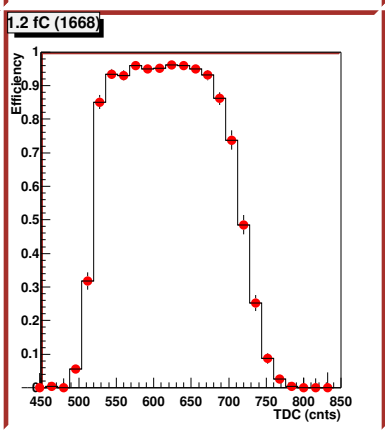


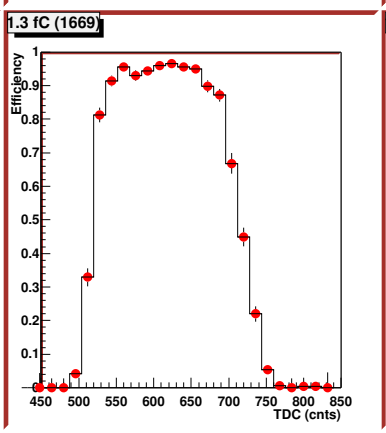


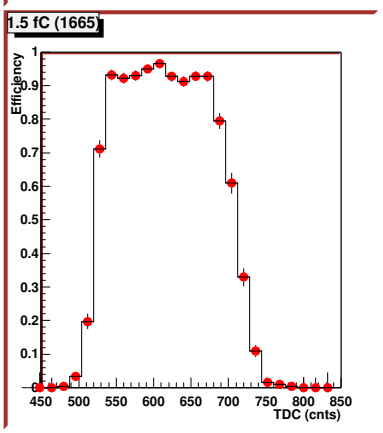


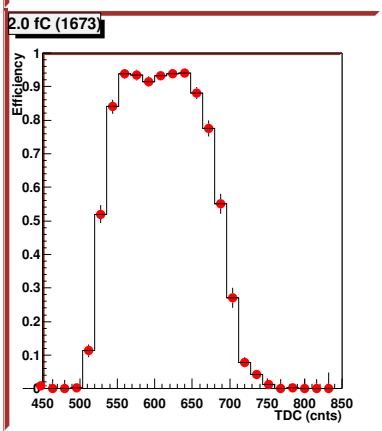


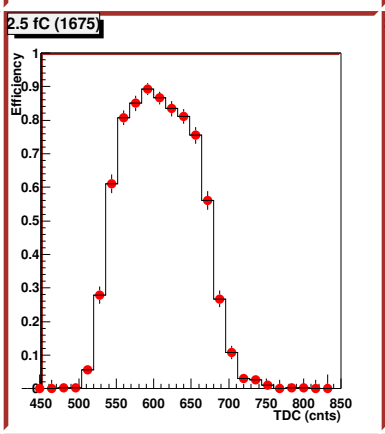


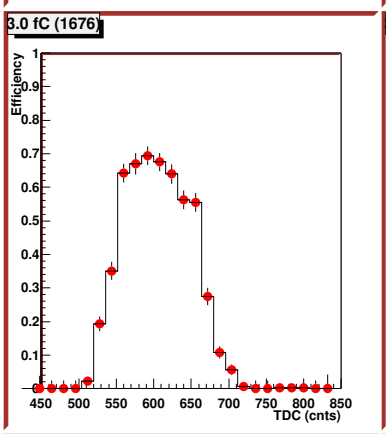


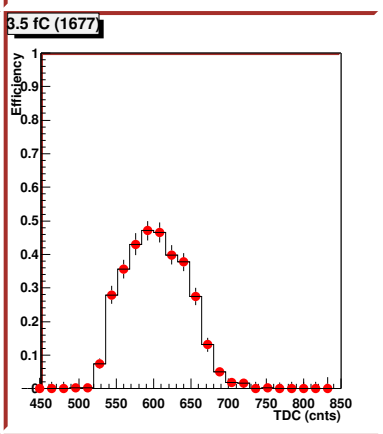


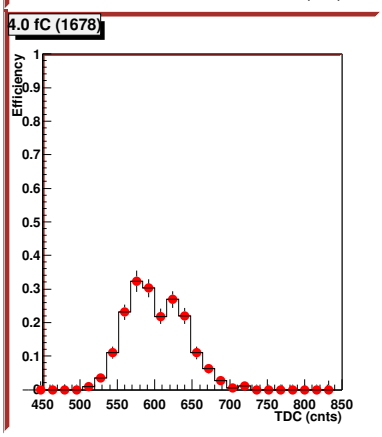


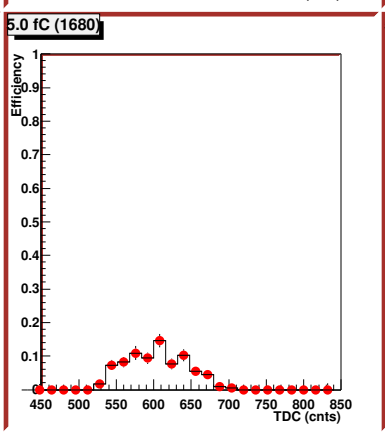


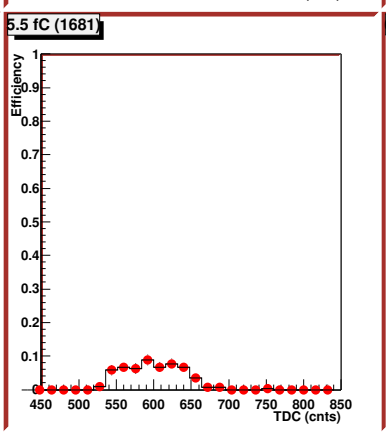


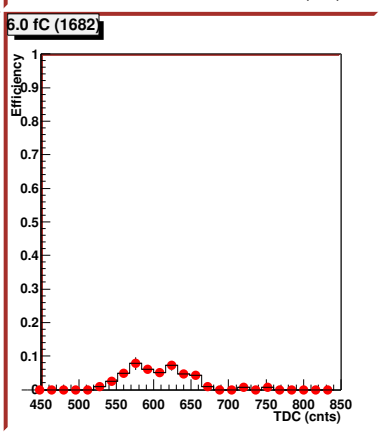




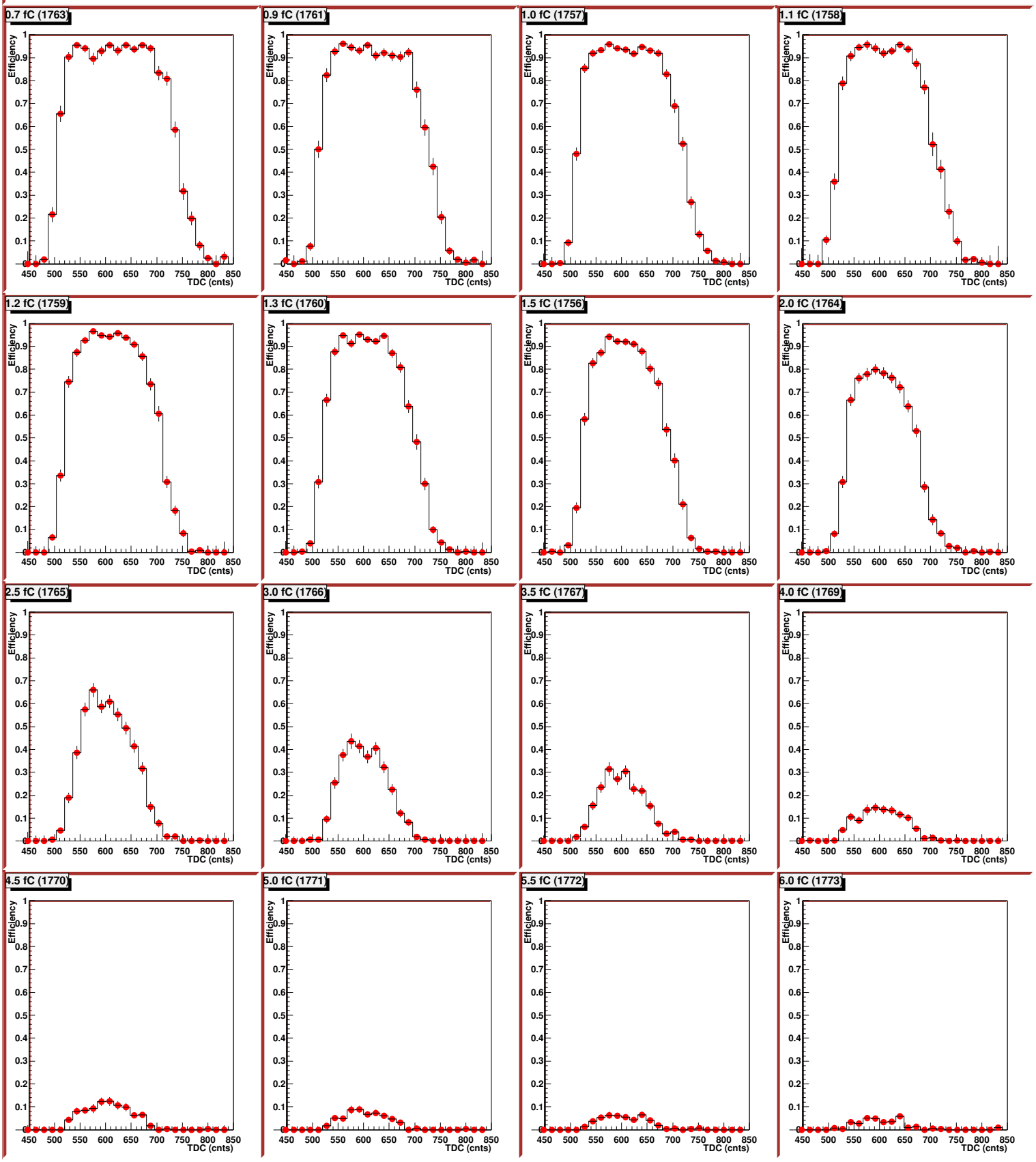




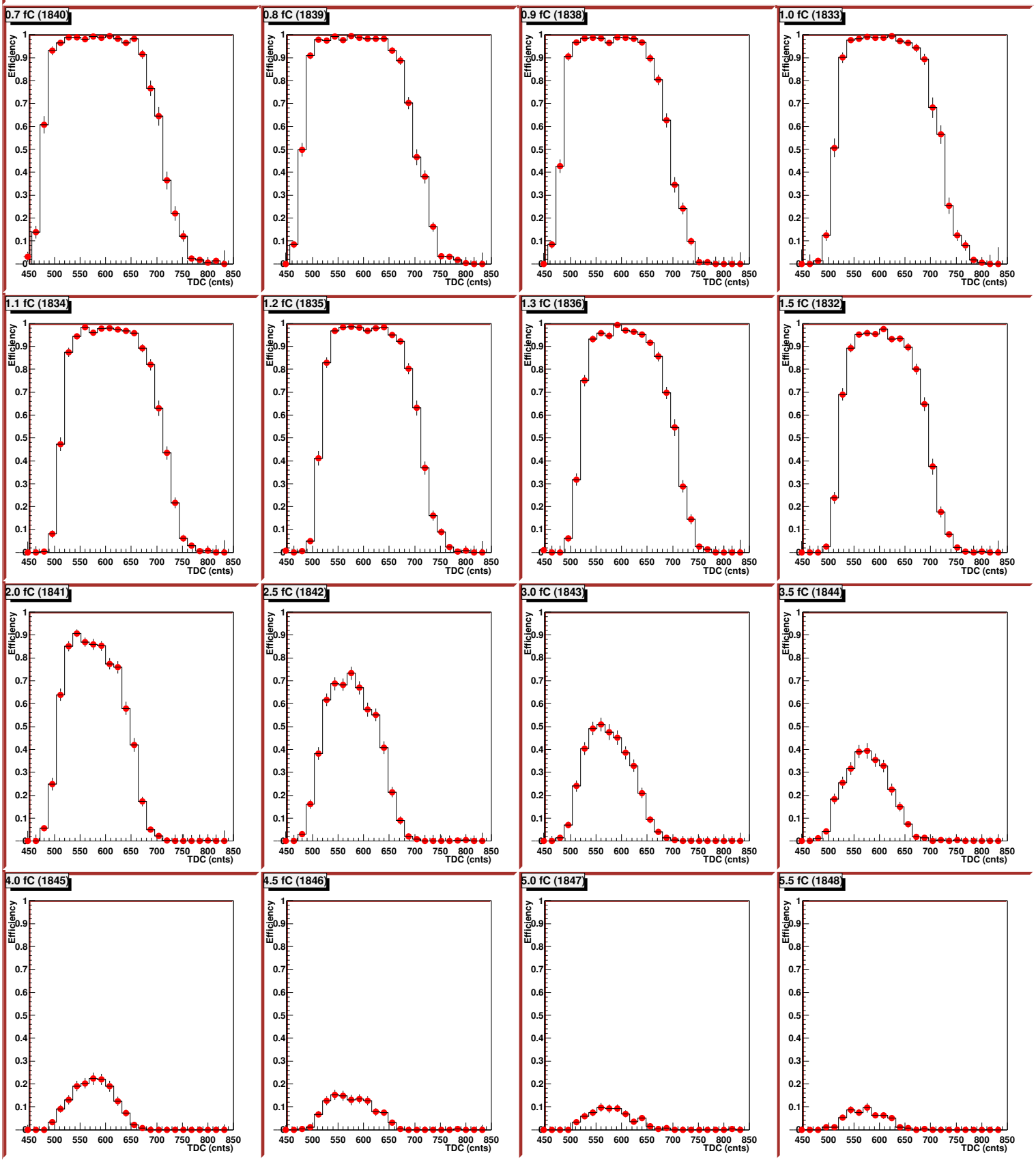




RLT5-0 threshold scan 160 V, max angle, B=1.65 T

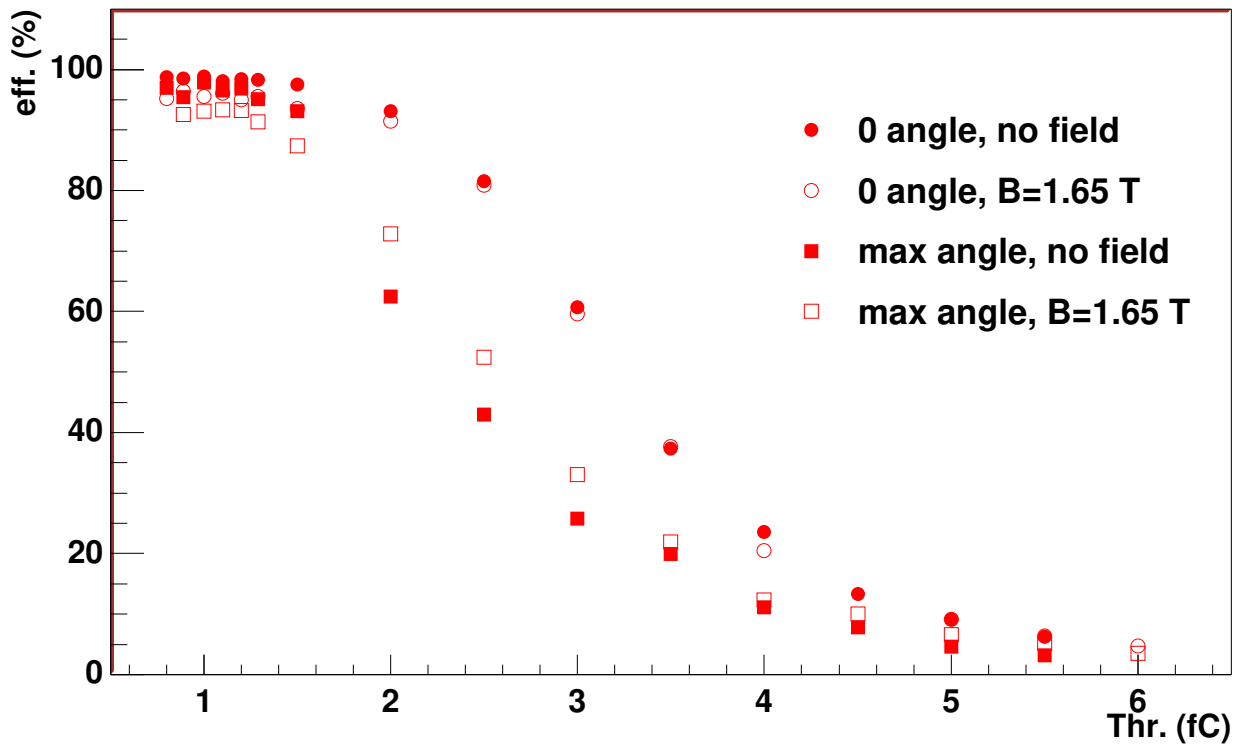


RLT5-0 threshold scan 160 V, max angle, no field

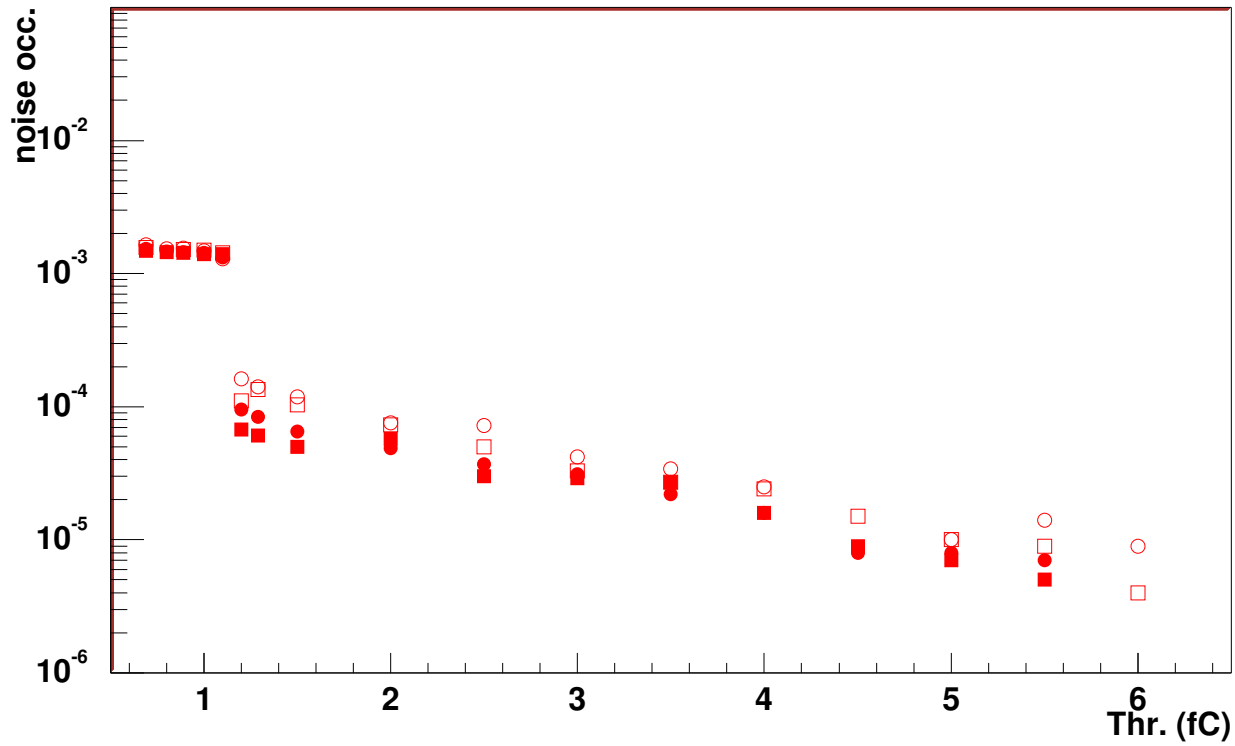


RLT5: Scurve 160 V

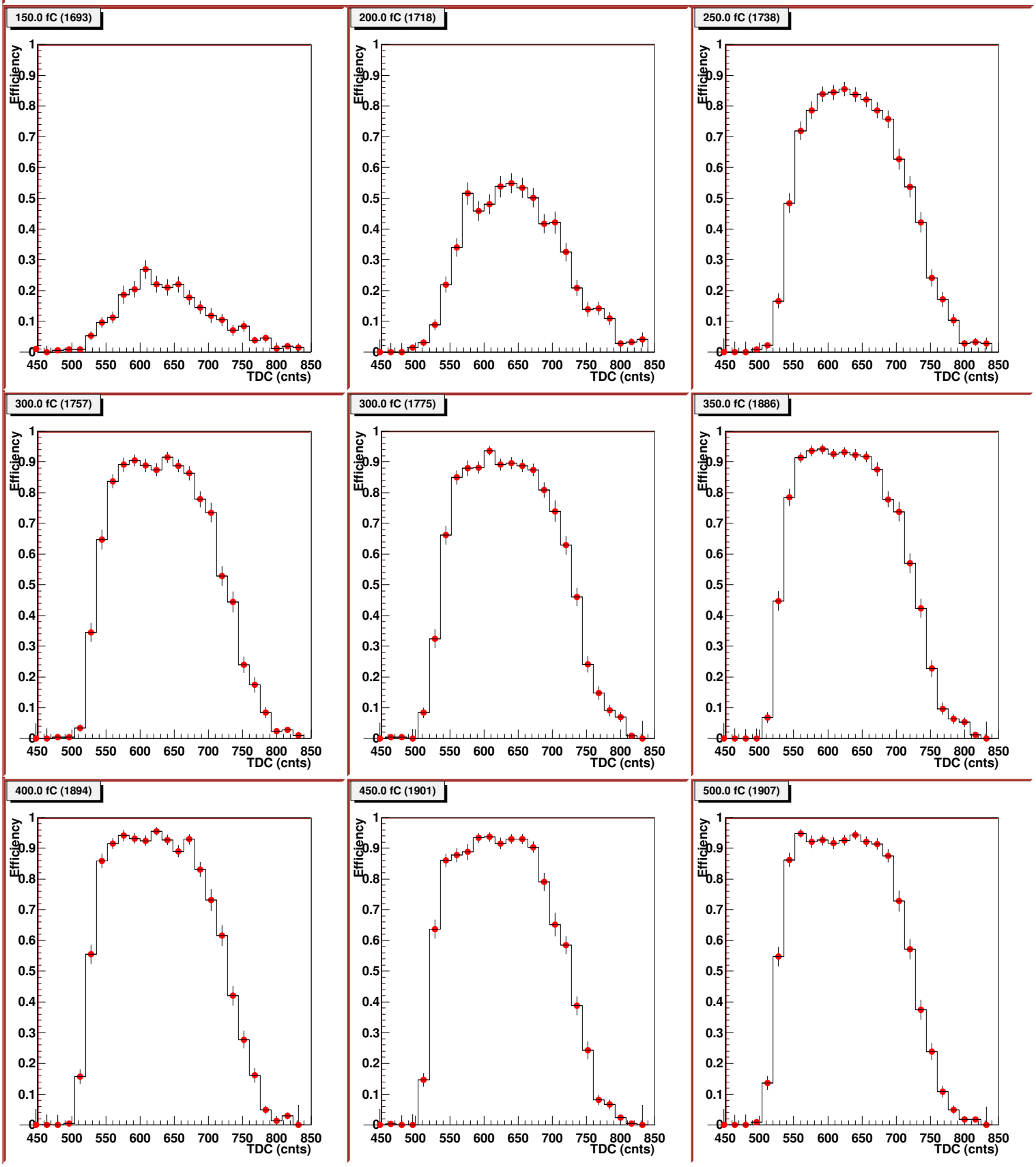
Efficiency



Noise occupancy

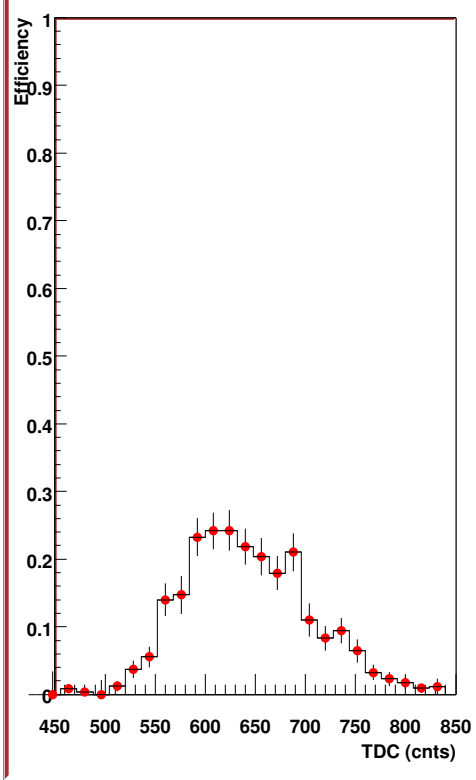


RLT9 bias scan 1 fC, max angle, B=1.65 T

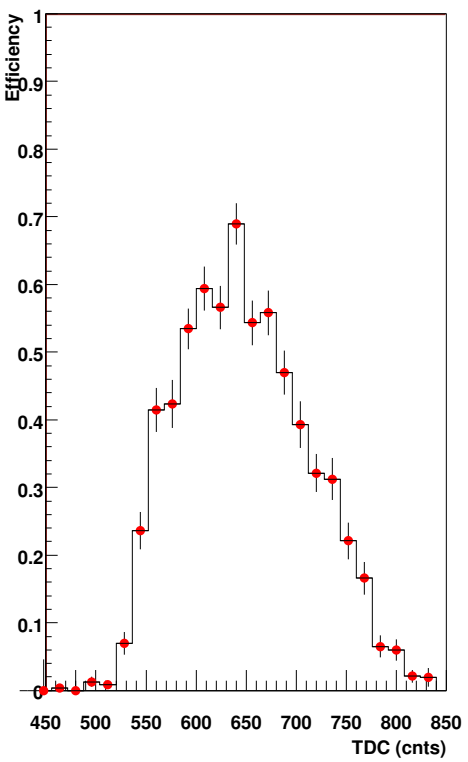


RLT9 bias scan 1 fC, max angle, no field

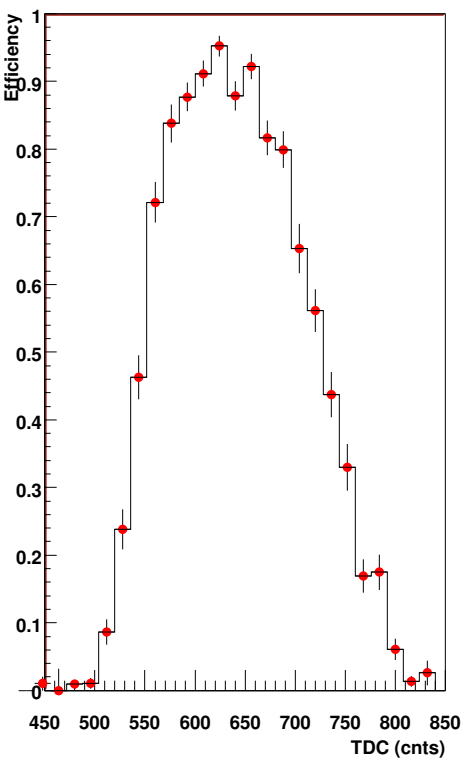
150 V (1778) : 27.4 ns



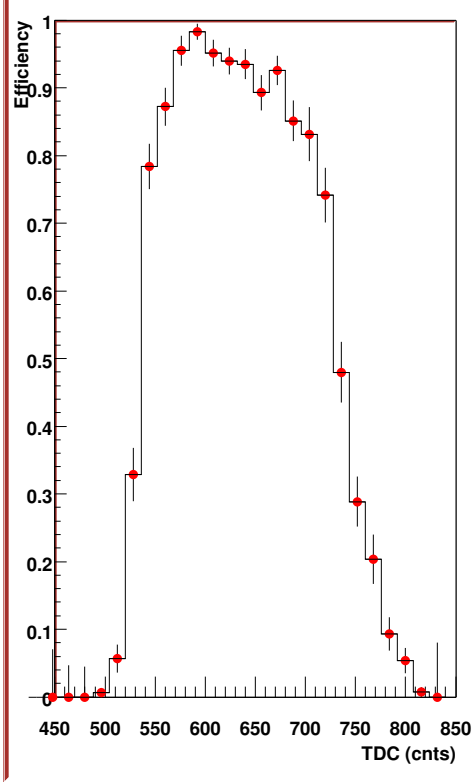
200 V (1796) : 35.8 ns



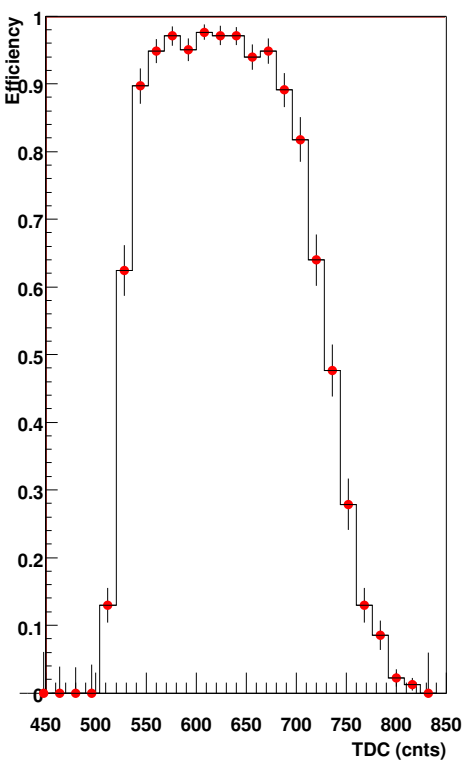
250 V (1814) : 37.9 ns



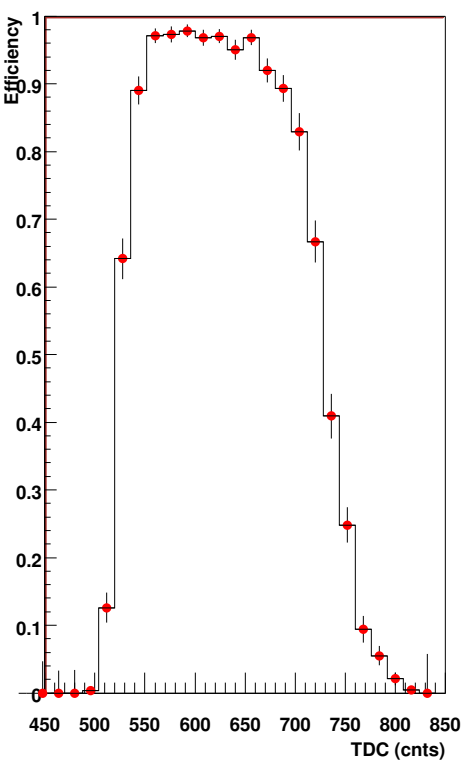
300 V (1833) : 41.3 ns



400 V (1919) : 42.0 ns

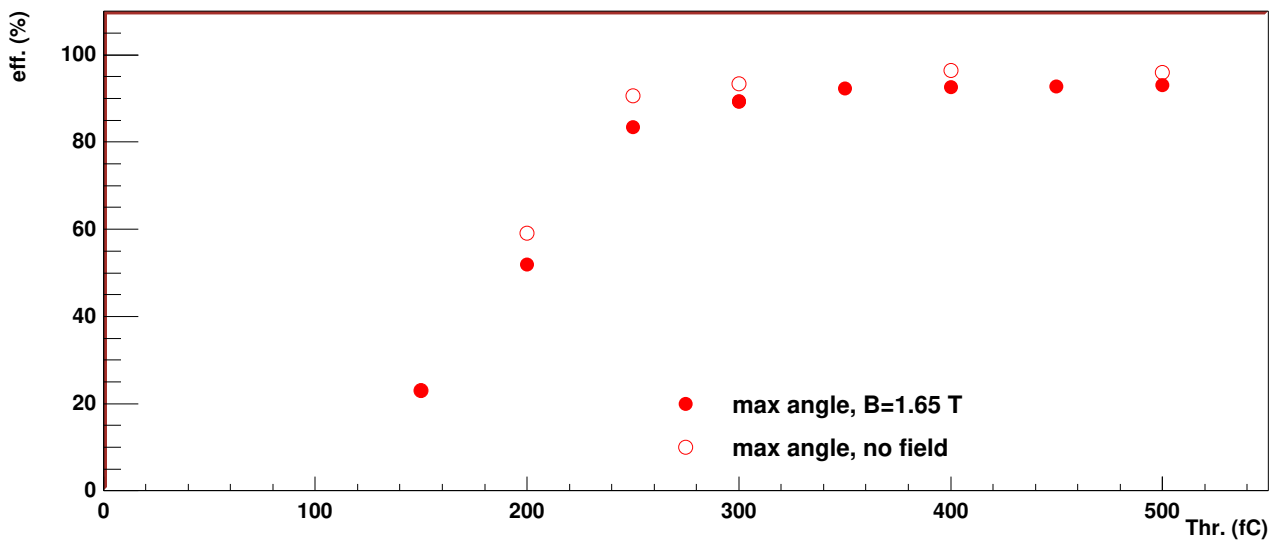


500 V (1913) : 41.6 ns

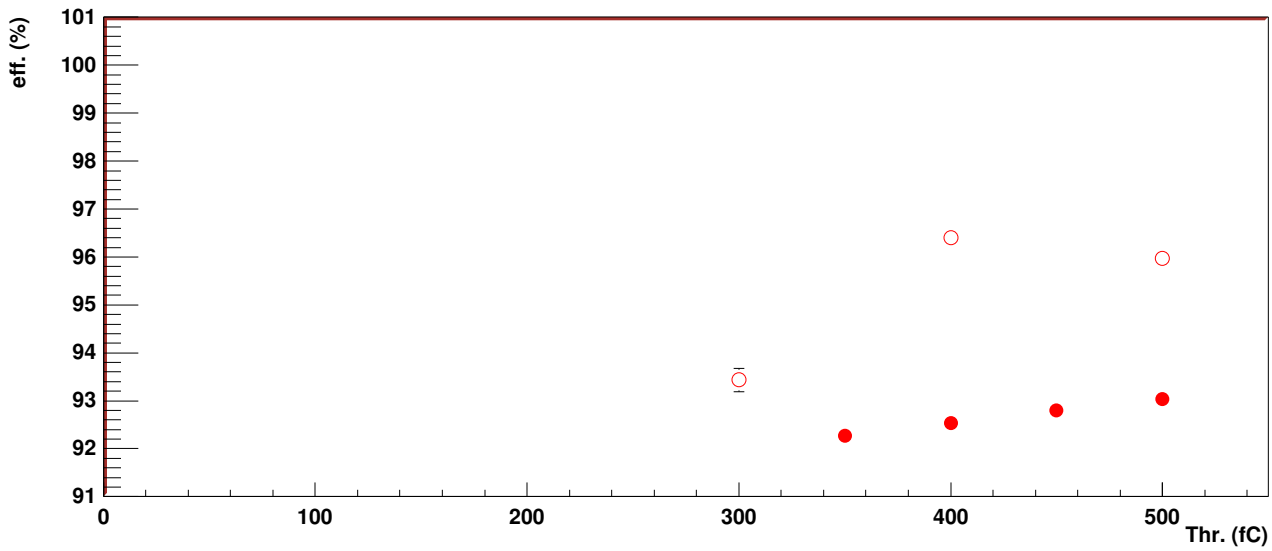


RLT9: Bias scan 1 fC, max angle

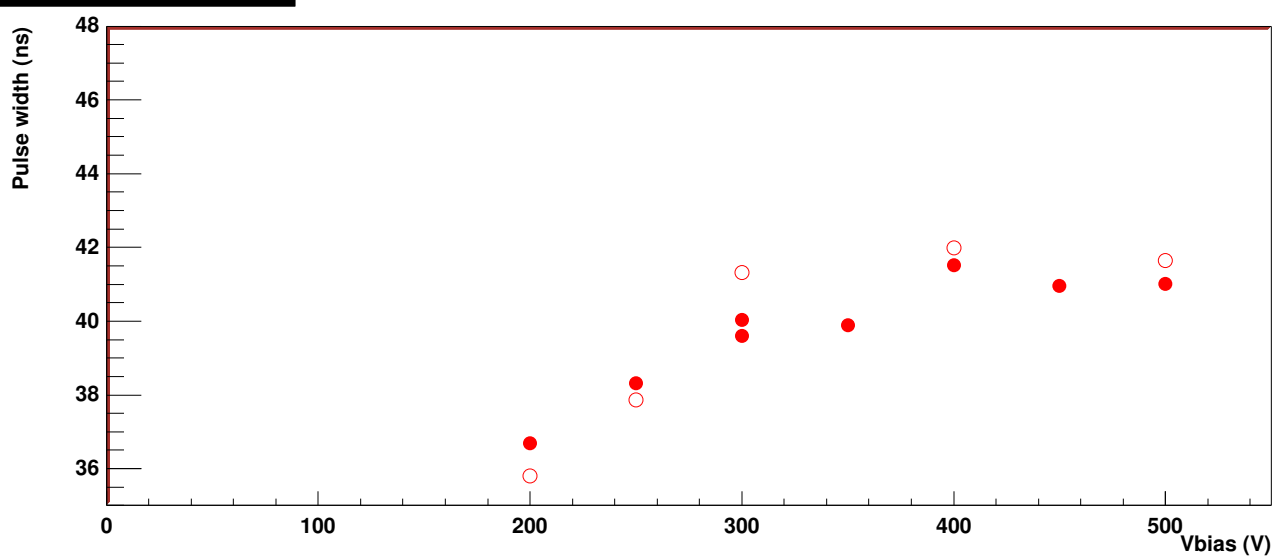
Efficiency



Efficiency

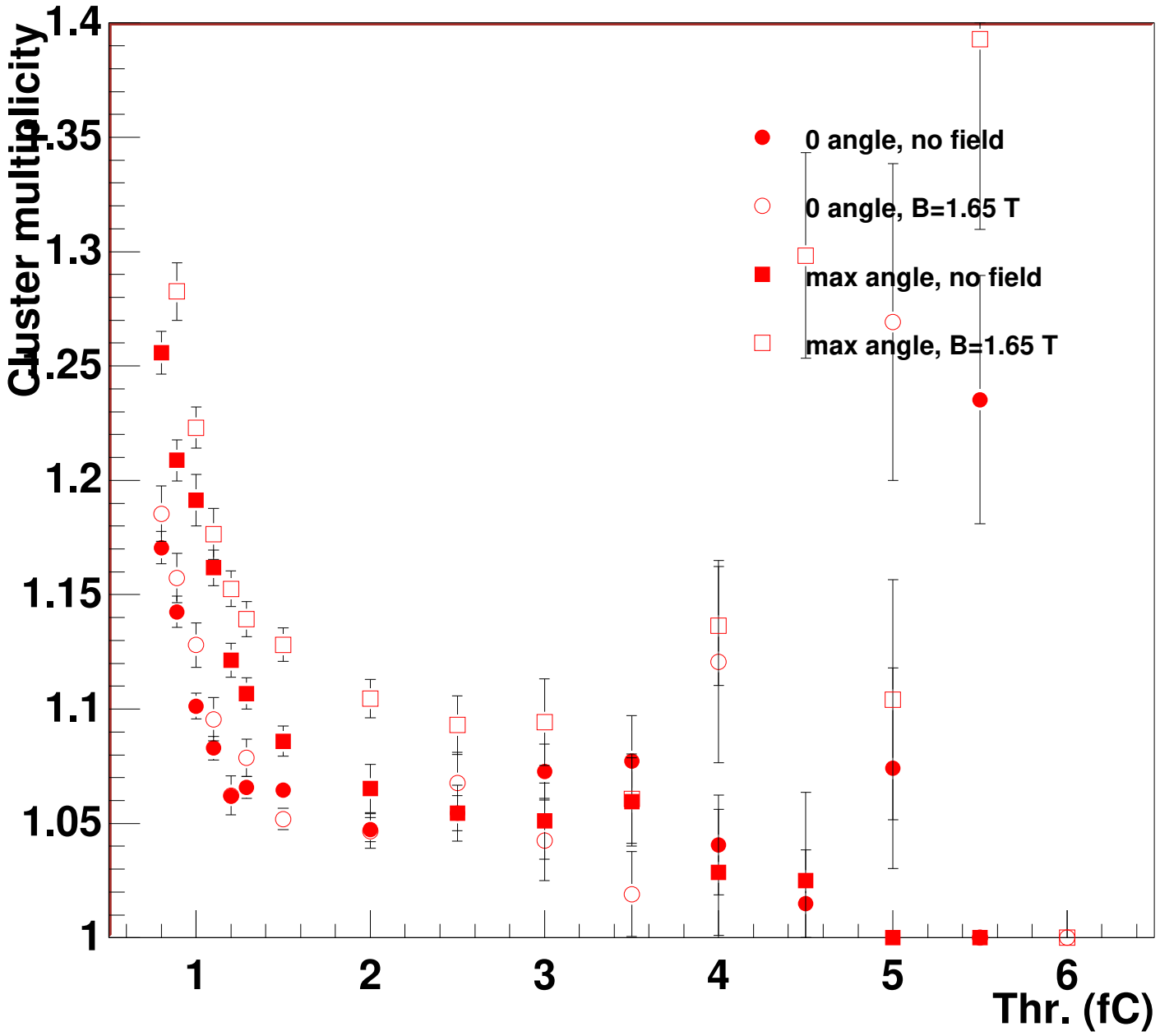


Pulse width

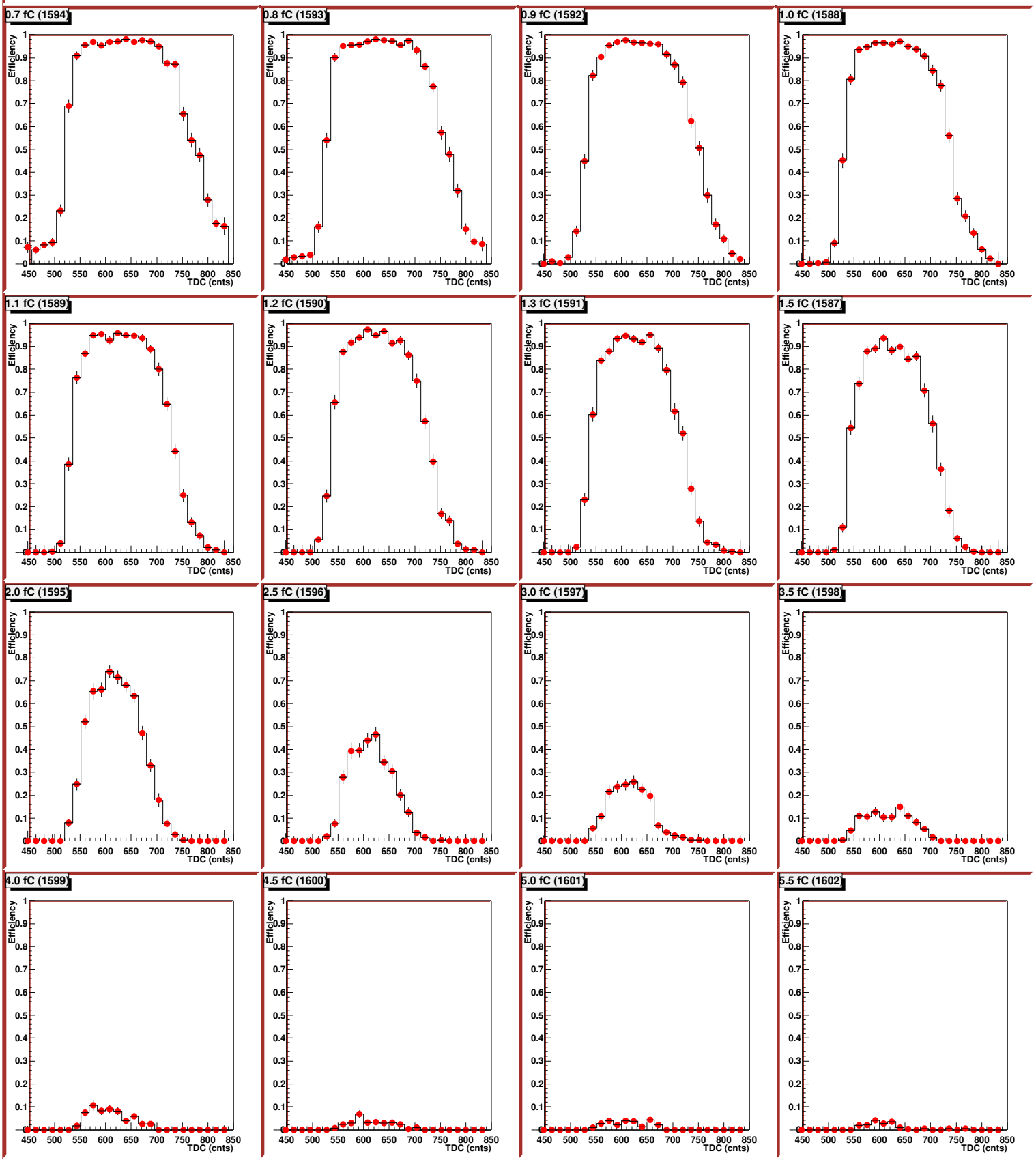


RLT9: Av. cluster multiplicity 300 V

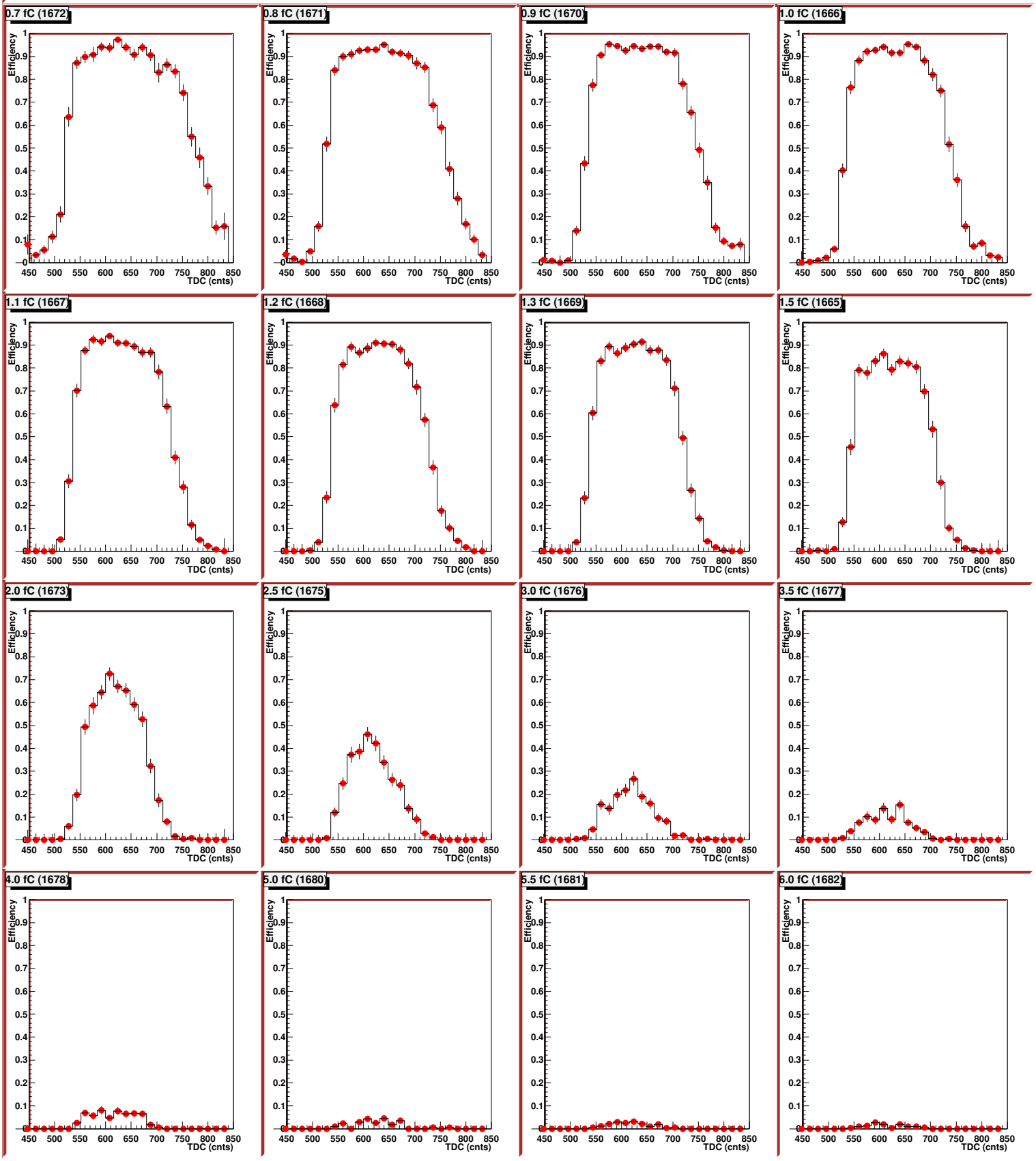
efficient clusters



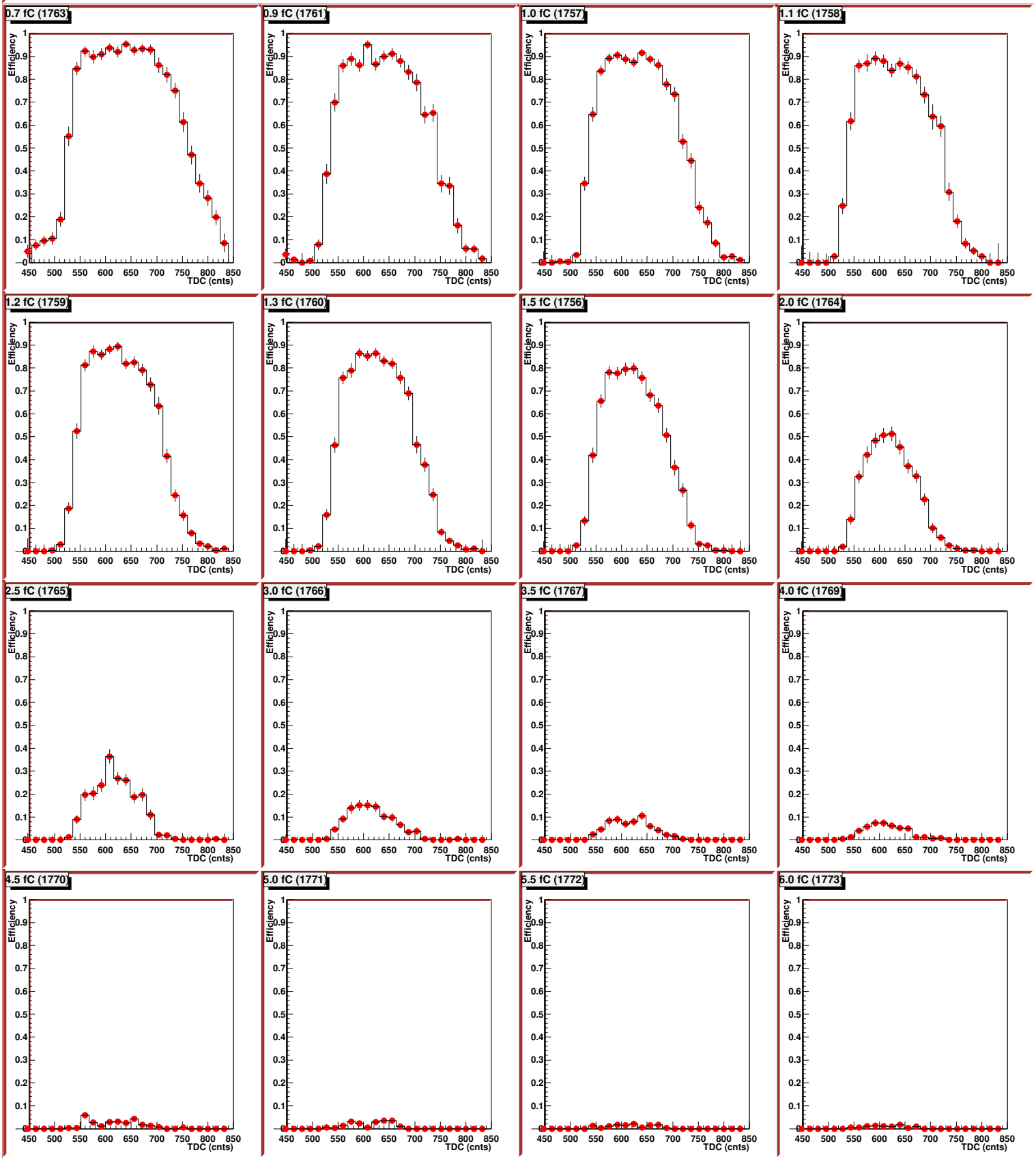
RLT9 threshold scan 300 V, 0 angle, no field



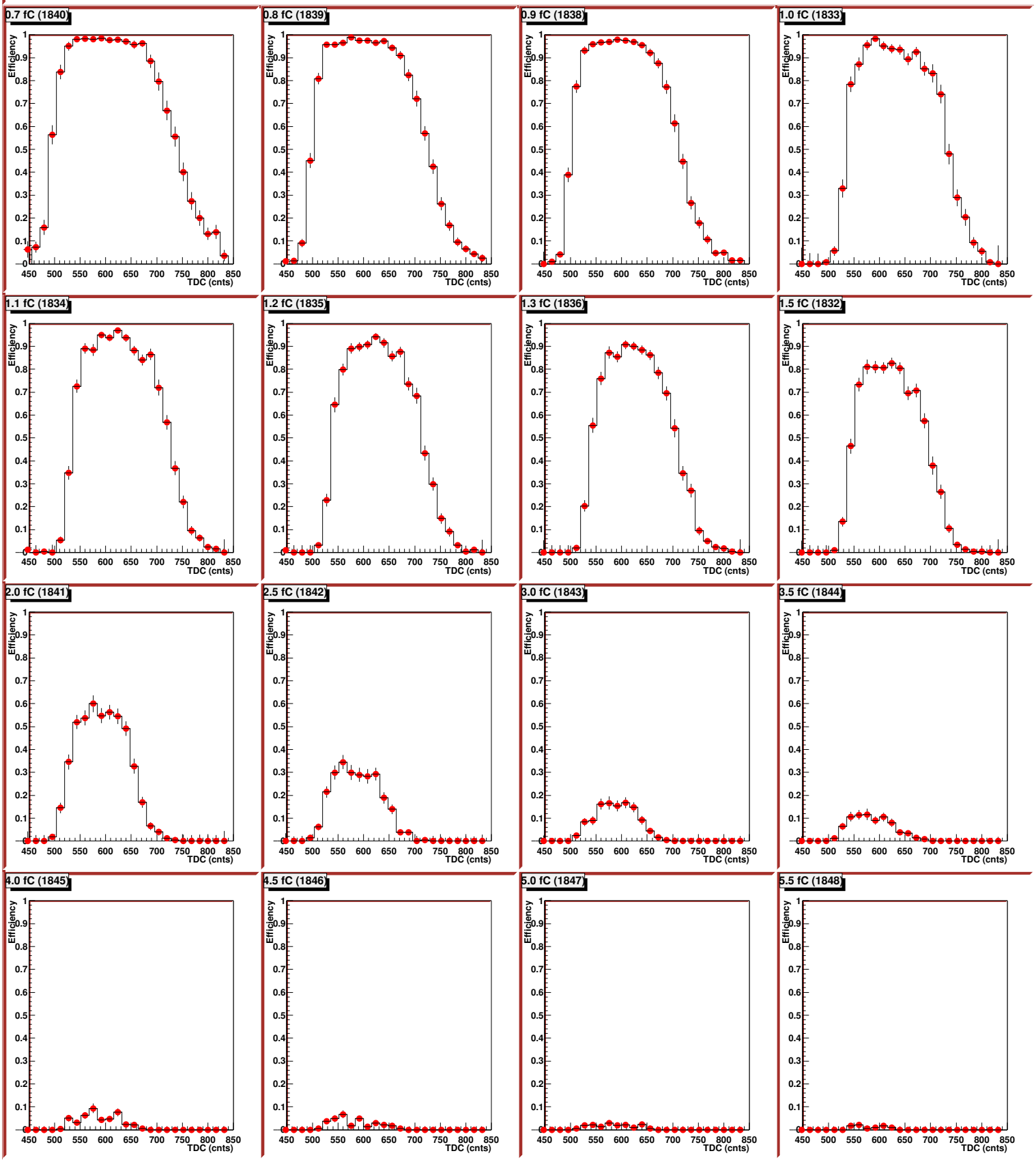
RLT9 threshold scan 300 V, 0 angle, B=1.65 T



RLT9 threshold scan 300 V, max angle, B=1.65 T

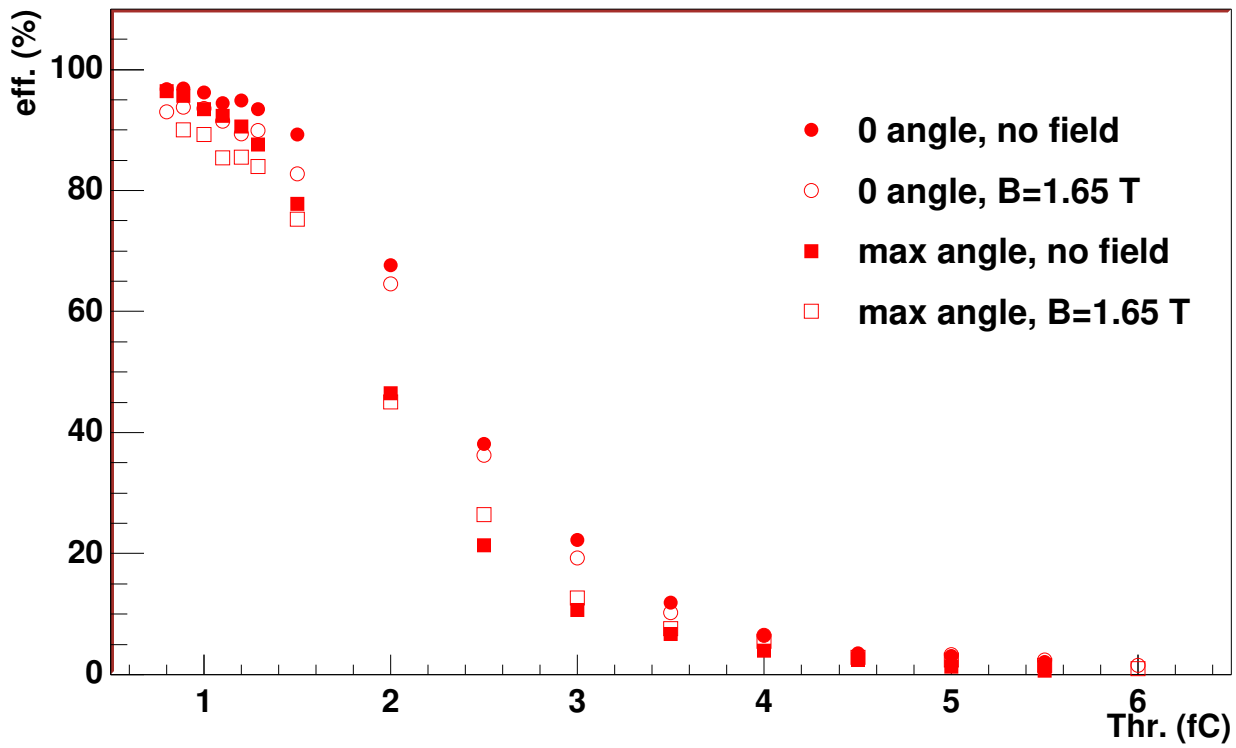
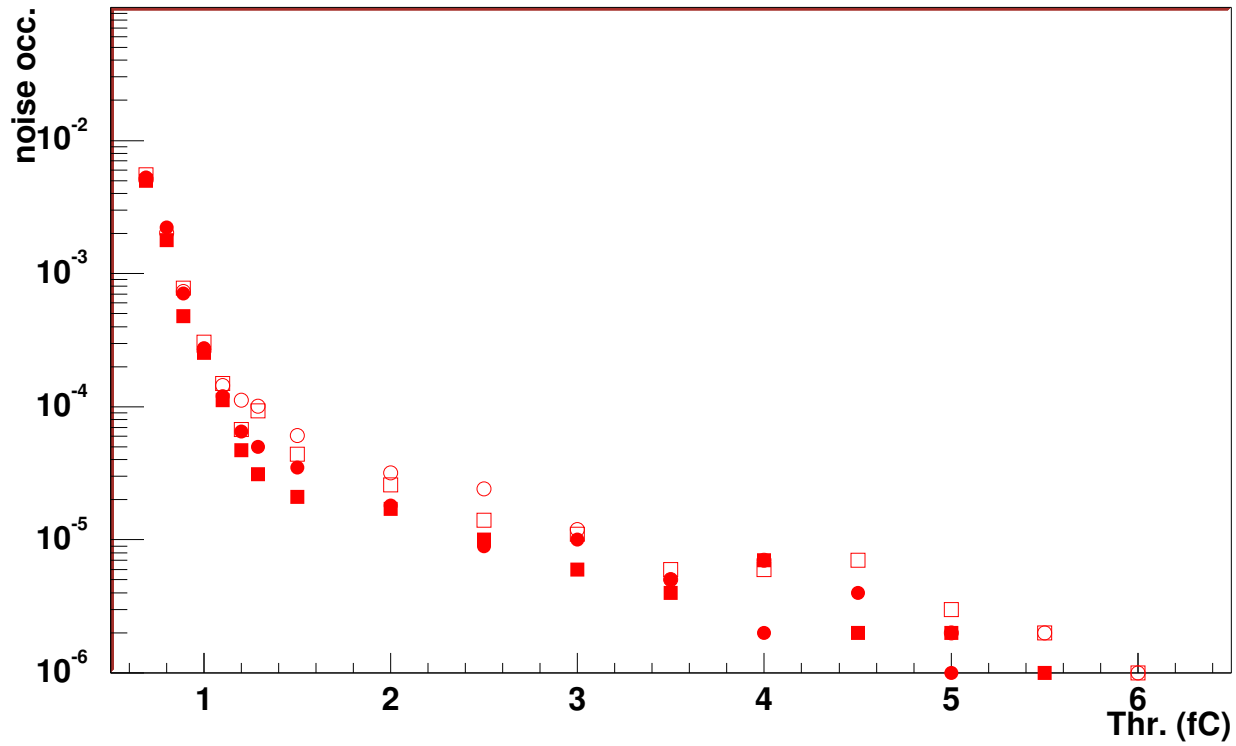


RLT9 threshold scan 300 V, max angle, no field



RLT9: Scurve 300 V

Efficiency



Noise occupancy